

PCTEST

7185 Oakland Mills Road, Columbia, MD 21046 USA Tel. 410.290.6652 / Fax 410.290.6654 http://www.pctest.com



HEARING AID COMPATIBILITY

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea Date of Testing: 1/18/2021 - 2/23/2021 Test Site/Location: PCTEST, Columbia, MD, USA Test Report Serial No.: 1M2101040001-18-R1.A3L Date of Issue: 3/3/2021

FCC ID: A3LSMA426U

APPLICANT: SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: RF Emissions Testing

Application Type: Certification
FCC Rule Part(s): CFR §20.19(b)
HAC Standard: ANSI C63.19-2011

CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017

285076 D01 HAC Guidance v05

285076 D02 T-Coil testing for CMRS IP v03

DUT Type: Portable Handset **Model:** SM-A426U

Additional Model(s): SM-A426U1/DS, SM-S426DL, SM-A426U1 Test Device Serial No.: Pre-Production Sample [S/N: 13433, 51730]

C63.19-2011 HAC Category: M3 (RF EMISSIONS CATEGORY)

Note: This revised Test Report (S/N: 1M2101040001-18-R1.A3L) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.





Authorized Test Lab
Lab Code: 20080603-00





FCC ID: A3LSMA426U	POTEST Proud to be post of the common	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 1 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage 1 01 103

© 2021 PCTEST REV 3.5.M

TABLE OF CONTENTS

1.	INTRODUCTION	3
2.	DUT DESCRIPTION	4
3.	ANSI/IEEE C63.19 PERFORMANCE CATEGORIES	6
4.	SYSTEM SPECIFICATIONS	7
5.	TEST PROCEDURE	12
6.	SYSTEM CHECK	14
7.	MODULATION INTERFERENCE FACTOR	17
8.	RF CONDUCTED POWER MEASUREMENTS	25
9.	JUSTIFICATION OF HELD TO EAR MODES TESTED	31
10.	LTE TDD UPLINK-DOWNLINK CONFIGURATION	33
11.	OVERALL MEASUREMENT SUMMARY	35
12.	EQUIPMENT LIST	39
13.	MEASUREMENT UNCERTAINTY	40
14.	TEST DATA	41
15.	CALIBRATION CERTIFICATES	57
16.	CONCLUSION	98
17.	REFERENCES	99
18.	TEST PHOTOGRAPHS	101

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 2 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 2 of 103

1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-86581 to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid in-vitu

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 3 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		raye 3 01 103

© 2021 PCTEST

2. DUT DESCRIPTION



FCC ID: A3LSMA426U

Manufacturer: Samsung Electronics Co., Ltd.

129, Samsung-ro, Maetan dong,

Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea

Model: SM-A426U

Additional Model(s): SM-A426U1/DS, SM-S426DL, SM-A426U1

Serial Number: 13433, 51730
Antenna Configurations: Internal Antenna
DUT Type: Portable Handset

I. Power Reduction for WIFI

This device uses an independent fixed level power reduction mechanism for all 2.4GHz and 5GHz 20MHz and 40MHz BW WIFI operations during voice or VoIP held to ear scenarios. Reduced powers were used to evaluate for low-power exemption in Section 9.II for WIFI. Detailed descriptions of the power reduction mechanism are included in the operational description.

II. LTE Band Selection

This device supports the following pair of LTE bands with similar frequencies: LTE B66 & B4. LTE B66 has a higher target power than B4 and shares the same transmission path. Since the supported frequency span for the smaller LTE band is completely covered by the larger LTE band, only the larger LTE band (LTE B66) was evaluated for hearing-aid compliance. LTE B5 and B2 are LTE anchor bands for dual connectivity (EN-DC) scenarios between LTE and NR so they were additionally evaluated as independent LTE bands.

III. NR Band Selection

This device supports the following pair of NR bands with similar frequencies: NR n2 & n25. This pair of NR bands has the same target power and shares the same transmission path. Since the supported frequency span for the smaller NR band is completely covered by the larger NR band, only the larger NR band (NR n25) was evaluated for hearing-aid compliance.

IV. Device Serial Numbers

Several samples with identical hardware were used to support HAC testing. The manufacturer has confirmed that the device(s) tested have the same physical, mechanical, and thermal characteristics are within operational tolerances expected for production units. The serial numbers used for each test are indicated alongside the results in Section 11.

FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 4 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 4 01 103

© 2021 PCTEST REV

Table 2-1 A3LSMA426U HAC Air Interfaces

				l HAC All Illerlaces	
Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service
	835	VO	Vos	Voc. MIEL or DT	CMDS Voice
CDMA	1900	, vo	Yes	Yes: WIFI or BT	CMRS Voice
	EvDO	VD	No ¹	Yes: WIFI or BT	Google Duo
	850	vo	Yes	Yes: WIFI or BT	CMRS Voice
GSM	1900	VO	163	res. will of bi	CIVINS VOICE
	GPRS/EDGE	VD	No ¹	Yes: WIFI or BT	Google Duo
	850				
UMTS	1700	VD	No ¹	Yes: WIFI or BT	CMRS Voice
UIVITS	1900				
	HSPA	VD	No ¹	Yes: WIFI or BT	Google Duo
	680 (B71)		No ^{1 2}		
	700 (B12)				
	780 (B13)				
	790 (B14)			Yes: WIFI or BT	VoLTE, Google Duo
LTE (FDD)	850 (B5)		No ¹		
	850 (B26)	1			
	1700 (B4)	VD			
	1700 (B66)				
	1900 (B2)				
	1900 (B25)				
	2300 (B30)				
	2500 (B7)				
LTE (TDD)	2600 (B41)	1/5		V. MIEL DT	VALTE CANAL DA
LTE (TDD)	3600 (B48)	VD	Yes	Yes: WIFI or BT	VoLTE, Google Duo
	680 (n71)		No ^{1 2}		
	850 (n5)				
NR (FDD)	1700 (n66)	VD	N = 1	Yes: WIFI or BT	Google Duo
	1900 (n2)		No ¹		
	1900 (n25)				
	2600 (n41)		V		
ND (TDD)	3700 (n77)	1	Yes	V. MIEL DT	Court B
NR (TDD)	28000 (n261)	VD	2	Yes: WIFI or BT	Google Duo
	39000 (n260)		No ³		
	2450				
	5200 (U-NII 1)]			
WIFI	5300 (U-NII 2A)	VD	No ¹	Yes: CDMA, GSM, UMTS, LTE, or NR	VoWIFI, Google Duo
	5500 (U-NII 2C)				
	5800 (U-NII 3)				
BT	2450	DT	No	Yes: CDMA, GSM, UMTS, LTE, or NR	N/A
Type Transport			Notes:		
VO = Voice Only				or MIF and low-power exemption.	and ECC UAC and Latter
וט = וע algital Dai	a - Not intended for	voice Services	IZ. LIE B/1 and	d NR n71, while outside the scope of ANSI C63.19	and FCC HAC regulations, were

DT = Digital Data - Not intended for Voice Services VD = CMRS and/or IP Voice over Data Transport

2. LTE B71 and NR n71, while outside the scope of ANSI C63.19 and FCC HAC regulations, were additionally tested according to the existing HAC procedures with currently available test equipment.

3. n260 and n261 are currently outside the scope of ANSI C63.19 and FCC HAC regulations therefore they were not evaluated.

Ī	FCC ID: A3LSMA426U	PCTEST*	НА	C (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Γ	Filename:	Test Dates:		DUT Type:		Dogg F of 102
	1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021		Portable Handset		Page 5 of 103

3. ANSI/IEEE C63.19 PERFORMANCE CATEGORIES

I. RF EMISSIONS

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	Telephone RF Parameters		
Near field Category	E-field emissions CW dB(V/m)		
	f < 960 MHz		
M1	50 to 55		
M2	45 to 50		
M3	40 to 45		
M4	< 40		
	f > 960 MHz		
M1	40 to 45		
M2	35 to 40		
М3	30 to 35		
M4	< 30		
Table 3-1 WD near-field categories as defined in ANSI C63.19-2011			

FCC ID: A3LSMA426U	PCTEST: Froud to be port of the second	— HAC (REEMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 6 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 6 of 103

4. SYSTEM SPECIFICATIONS

EF3DV3 E-Field Probe Description

Construction: One dipole parallel, two dipoles normal to probe axis

Built-in shielding against static charges

Calibration: In air from 30 MHz to 6.0 GHz

(absolute accuracy ±5.1%, k=2)

Frequency: 30 MHz to > 6 GHz;

Linearity: ± 0.2 dB (30 MHz to 6 GHz)

Directivity $\pm 0.2 \text{ dB}$ in air (rotation around probe axis)

± 0.4 dB in air (rotation normal to probe axis)

Dynamic Range 2 V/m to > 1000 V/m

(M3 or better device readings fall well below diode

compression point)

Linearity: ± 0.2 dB

Dimensions Overall length: 337 mm (Tip: 20 mm)

Tip diameter: 4.0 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 1.5 mm



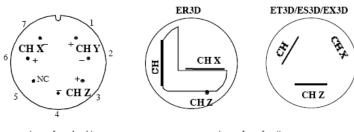
Figure 4-1 E-field Free-space Probe

Probe Tip Description

HAC field measurements take place in the close near field with high gradients. Increasing the measuring distance from the source will generally decrease the measured field values (in case of the validation dipole approx. 10% per mm).

The electric field probes have an irregular internal geometry because it is physically not possible to have the 3 orthogonal sensors situated with the same center. The effect of the different sensor centers is accounted for in the HAC uncertainty budget ("sensor displacement").

Connector Plan



(seen from back) (seen from front)

The antistatic shielding inside the probe is connected to the probe connector case.

FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 7 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage / 01 103

© 2021 PCTEST REV 3.

Equation 1

Conversion of Connector Voltage u, to E-Field E,

$$E_i = \sqrt{\frac{u_i + (u_i^2 \cdot CF)/(DCP)}{Norm_i \cdot ConvF}}$$

whereby

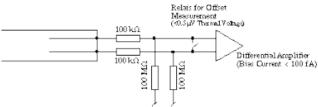
E_i: electric field in V/m

 u_i : voltage of channel i at the connector in μV Norm: sensitivity of channel i in $\mu V/(V/m)^2$ enhancement factor in liquid (ConvF=1 for Air)

DCP: diode compression point in μV

CF: signal crest factor (peak power/average power)

Conditions of Calibration



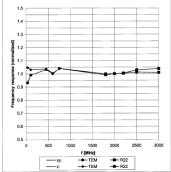
Please note:

- a lower input impedance of the amplifier will result in different sensitivity factors Norm, and DCP
- · larger bias currents will cause higher offset

Probe Response to Frequency

The E-field sensors have inherently a very flat frequency response. They are calibrated with a number of frequencies resulting in a common calibration factor, with the frequency behavior documented in the calibration certificate (See also below).





Uncertainty of Frequency Response of E-field: ± 6.3% (k=2

Figure 4-2 E-Field Probe Frequency Response

FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 9 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 8 of 103

© 2021 PCTEST REV 3.5.M

SPEAG Robotic System

E-field measurements are performed using the DASY5 automated dosimetric assessment system. The DASY5 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland and consists of high precision robotics system (Staubli), robot controller, Intel CORE i7 computer, near-field probe, probe alignment sensor, and the HAC phantom. The robot is a six-axis industrial robot performing precise movements to position the probe to the location (points) of maximum electromagnetic field (EMF).



Figure 4-3 SPEAG Robotic System

System Hardware

A cell controller system contains the power supply, robot controller, teach pendant (Joystick), and a remote control used to drive the robot motors. The PC consists of the computer with operating system and RF Measurement Software DASY5 v52.8 (with HAC Extension), A/D interface card, monitor, mouse, and keyboard. The Staubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit that performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

FCC ID: A3LSMA426U	PCTEST: Frond to the post of the security	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 0 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 9 of 103

System Electronics

The DAE consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.

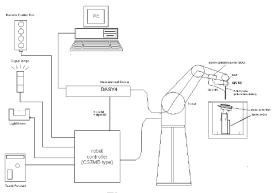


Figure 4-4 SPEAG Robotic System Diagram

DASY5 Instrumentation Chain

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power. The formula for each channel can be given as:

$$\begin{aligned} V_i &= U_i + U_i^2 \cdot \frac{cf}{dcp_i} \\ \text{with} \quad V_i &= \text{compensated signal of channel i} & (i = x, y, z) \\ U_i &= \text{input signal of channel i} & (i = x, y, z) \\ cf &= \text{crest factor of exciting field} & (\text{DASY parameter}) \\ dcp_i &= \text{diode compression point} & (\text{DASY parameter}) \end{aligned}$$

FCC ID: A3LSMA426U	PCTEST Proceed to the post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 10 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage 10 01 103

© 2021 PCTEST

From the compensated input signals the primary field data for each channel can be evaluated:

E – field
probes :
$$E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$$

with V_i = compensated signal of channel i (i = x, y, z) $Norm_i$ = sensor sensitivity of channel i (i = x, y, z)

 $\mu V/(V/m)^2$ for E-field Probes

ConvF = sensitivity enhancement in solution

 E_i = electric field strength of channel i in V/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

The measurement/integration time per point, as specified by the system manufacturer is >500ms.

The signal response time is evaluated as the time required by the system to reach 90% of the expected final value after an on/off switch of the power source with an integration time of 500ms and a probe response time of <5 ms. In the current implementation, DASY5 waits longer than 100ms after having reached the grid point before starting a measurement, i.e., the response time uncertainty is negligible.

If the device under test does not emit a CW signal, the integration time applied to measure the electric field at a specific point may introduce additional uncertainties due to the discretization. The tolerances for the different systems had the worst-case of 2.6%.

Environmental Conditions

Environmental conditions such as temperature and relative humidity are monitored to ensure there are no impacts on system specifications. Proper voltage and power line frequency conditions are maintained with three phase power sources. Environmental noise and reflections are monitored through system checks.

FCC ID: A3LSMA426U	PCTEST: Froad to be port of the second	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 11 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 11 of 103

TEST PROCEDURE 5.

RF EMISSIONS

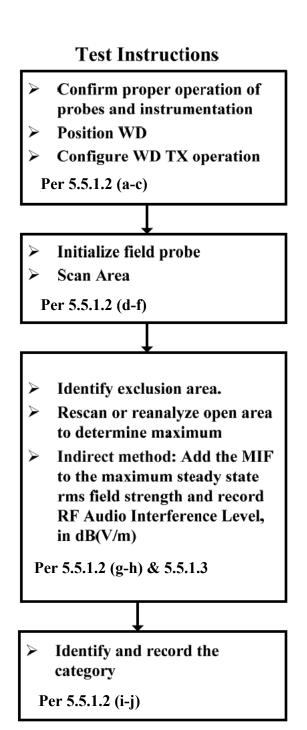


Figure 5-1 RF Emissions Flow Chart

	_			
FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 12 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 12 01 103

© 2021 PCTEST **REV 3.5.M**

Test Setup

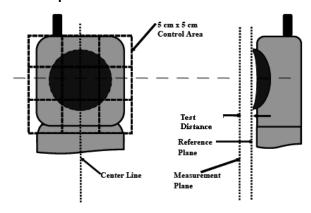


Figure 5-2
E-Field Emissions Test Setup Diagram (See Test Photographs for actual WD scan grid overlay)

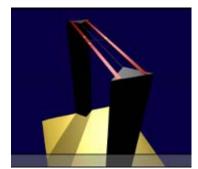


Figure 5-3 HAC Phantom

RF Emissions Test Procedure:

The following illustrate a typical RF emissions test scan over a wireless communications device:

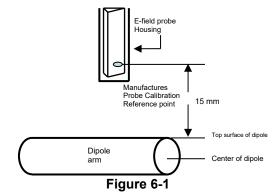
- 1. Proper operation of the field probe, probe measurement system, other instrumentation, and the positioning system was confirmed.
- 2. WD is positioned in its intended test position, acoustic output point of the device perpendicular to the field probe.
- 3. The WD operation for maximum rated RF output power was configured and confirmed with the base station simulator, at the test channel and other normal operating parameters as intended for the test. The battery was ensured to be fully charged before each test.
- 4. The center sub-grid was centered over the center of the acoustic output (also audio band magnetic output, if applicable). The WD audio output was positioned tangent (as physically possible) to the measurement plane.
- 5. A surface calibration was performed before each setup change to ensure repeatable spacing and proper maintenance of the measurement plane using the HAC Phantom.
- 6. The measurement system measured the field strength at the reference location.
- 7. Measurements at 2mm or 5mm increments in the 5 x 5 cm region were performed at a distance 15 mm from the center point of the probe measurement element to the WD. Of the 9 subgrids (see Figure 5-2), 3 contiguous subgrids may be excluded from the measurement in order to account for localized areas of higher field intensities. The center subgrid containing the acoustic output or audio band magnetic output may not excluded. A 360° rotation about the azimuth axis at the maximum interpolated position was measured. For the worst-case condition, the peak reading from this rotation was used in re-evaluating the HAC category.
- 8. The system performed a drift evaluation by measuring the field at the reference location. If the power drift deviated by more than 5%, the HAC test and drift measurements were repeated.

FCC ID: A3LSMA426U	PCTEST: Front to be port of a removed	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 12 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 13 of 103

System Check Parameters

The input signal was an un-modulated continuous wave. The following points were taken into consideration in performing this check:

- Average Input Power P = 100mW RMS (20dBm RMS) after adjustment for return loss
- The test fixture must meet the 2 wavelength separation criterion
- The proper measurement of the 15 mm probe to dipole separation, which is measured from top surface of the dipole to the calibration reference point of the sensor, defined by the probe manufacturer is shown in the following diagram:



Separation Distance from Dipole to Field Probe

RF power was recorded using both an average reading meter and a peak reading meter. Readings of the probe are provided by the measurement system.

To assure proper operation of the near-field measurement probe the input power to the dipole shall be commensurate with the full rated output power of the wireless device [e.g. - for a cellular phone wireless device the average peak antenna input power will be on the order of 100mW (20dBm) RMS] after adjustment for any mismatch.

II. Validation Procedure

A dipole antenna meeting the requirements given in C63.19 was placed in the position normally occupied by the WD.

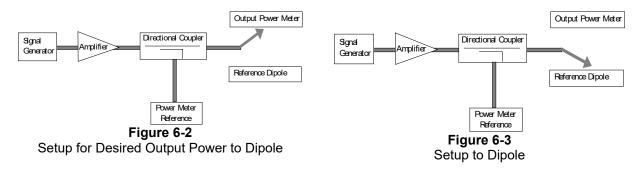
The length of the dipole was scanned, and the average peak value was recorded.

Measurement of CW

Using the near-field measurement system, scan the antenna over the radiating dipole and record the greatest field reading observed. Due to the nature of E-fields about free-space dipoles, the two E-field peaks measured over the dipole are averaged to compensate for non-parallelity of the setup (see manufacturer method on dipole calibration certificates, page 2). Field strength measurements shall be made only when the probe is stationary.

FCC ID: A3LSMA426U	PCTEST: Froud to be port of the security	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 14 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 14 of 103

© 2021 PCTEST **REV 3.5.M** RF power was recorded using both an average and a peak power reading meter.



Using this setup configuration, the signal generator was adjusted for the desired output power (100mW) at a specified frequency. The reference power from the coupled port of the directional coupler is recorded. Next, the output cable is connected to the reference dipole, as shown in Figure 6-3.

The input signal level was adjusted until the reference power from the coupled port of the directional coupler was the same as previously recorded, to compensate for the impedance mismatch between the output cable and the reference dipole. To assure proper operation of the near-field measurement probe the input power to the reference dipole was verified to the full rated output power of the wireless device. The dipole was secured in a holder in a manner to meet the 20 dB reflection. The near-field measurement probe was positioned over the dipole. The antenna was scanned over the appropriate sized area to cover the dipole from end to end. SPEAG uses 2D interpolation algorithms between the measured points. Please see below two dimensional plots showing that the interpolated values interpolate smoothly between 5mm steps for a free-space RF dipole:



2-D Raw Data from scan along dipole axis

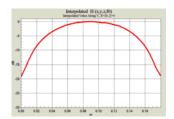
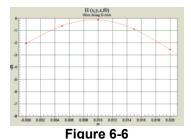


Figure 6-5
2-D Interpolated points from scan along dipole axis



2-D Raw Data from scan along transverse axis



2-D Interpolated points from scan along transverse axis

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 15 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 15 of 103

III. System Check Results

Validation Results

Date	Frequency (MHz)	Probe S/N	DAE S/N	Dipole S/N	Input Power (dBm)	E-field Result (V/m)	Target Field (V/m)	% Deviation				
	835			1190	20.0	106.5	105.4	1.0%				
1/18/2021	1880		665	1176	20.0	90.2	88.0	2.5%				
	2600	4035	4025		005	003	003		20.0	89.6	85.4	4.9%
1/25/2021	2000	4033		1013	20.0	90.2	85.4	5.6%				
2/22/2020	3500		1530	1005	20.0	88.2	84.4	4.5%				
1/25/2021	3900		665	1005	20.0	86.4	81.0	6.7%				

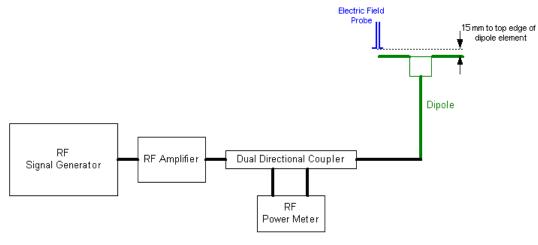


Figure 6-8 System Check Setup

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 16 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage 10 01 103

© 2021 PCTEST **REV 3.5.M**

7. MODULATION INTERFERENCE FACTOR

I. Measuring Modulation Interference Factors

For any specific fixed and repeatable modulated signal, a modulation interference factor (MIF, expressed in dB) may be determined that relates its interference potential to its steady-state RMS signal level or average power level. This factor is a function only of the audio-frequency amplitude modulation characteristics of the signal and is the same for field-strength and conducted power measurements. The MIF is valid only for a specific repeatable audio-frequency amplitude modulation characteristic; any change in modulation characteristic requires determination and application of a new MIF.

The MIF may be determined using a radiated RF field or a conducted RF signal:

- a. Using RF illumination or conducted coupling, apply the specific modulated signal in question to the measurement system at a level within its confirmed operating dynamic range.
- b. Measure the steady-state RMS level at the output of the fast probe or sensor.
- c. Measure the steady-state average level at the weighting output.
- d. Without changing the square-law detector or weighting system, and using RF illumination or conducted coupling, substitute for the specific modulated signal a 1 kHz, 80% amplitude modulated carrier at the same frequency and adjust its strength until the level at the weighting output equals the step c) measurement.
- e. Without changing the carrier level from step d), remove the 1 kHz modulation and again measure the steady-state RMS level indicated at the output of the fast probe or sensor.
- f. The MIF for the specific modulation characteristic is provided by the ratio of the step e) measurement to the step b) measurement, expressed in dB (20 × log[(step e)/(step b)]).

The following procedure was used to measure the MIF using the SPEAG Audio Interference Analyzer (AIA), Type No: SE UMS 170 CB, Serial No.: 1010:

- 1. The device was placed into a simulated call using a base station simulator or set to transmit using test software for a given mode.
- 2. The device was then set to continuously transmit at maximum power.
- 3. Using a coupler if needed, the device output signal was connected to the RF In port of the AIA, which was connected to a desktop computer. Alternatively, a radiated RF signal may be used with the AIA's built-in antenna.
- 4. The MIF measurement procedure in the DASY software was run, and the resulting MIF value was recorded.
- 5. Steps 1-4 were repeated for all CMRS air interfaces, frequency bands, and modulations.

The modulation interference factors obtained were applied to readings taken of the actual wireless device in order to obtain an accurate audio interference level reading using the formula:

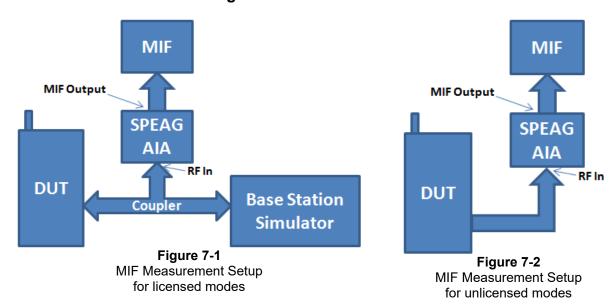
Audio Interference Level [dB(V/m)] = 20 * log[Raw Field Value (V/m)] + MIF (dB)

Because the MIF value is output power independent, MIF values for a given mode should be constant across all devices; however, per C63.19-2011 §D.7, MIF values should be measured for each device being evaluated. The voice modes for this device have been investigated in this section of the report.

FCC ID: A3LSMA426U	PCTEST* Road to be got of \$\infty\$ resources	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 17 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage 17 01 103

© 2021 PCTEST REV 3

II. MIF Measurement Block Diagrams



III. Measured Modulation Interference Factors:

Table 7-1 CDMA Modulation Interference Factors¹

	ODWA Woodulation interference Factors								
			C	ell		PCS			
Mode		908	22H	22H	22H	24E	24E	24E	
		564	1013	384	777	25	600	1175	
	RC1/SO3	3.10	3.11	3.07	3.06	3.10	3.09	3.05	
CDMA	RC1/SO55	-20.13	-20.32	-19.92	-19.95	-20.26	-20.11	-19.98	
	EvDO	-19.51	-19.35	-19.53	-19.44	-19.22	-19.26	-19.20	

Table 7-2 GSM Modulation Interference Factors¹

GOW Woodiation interference i actors								
Mode			GSM850		GSM1900			
IVIC	oue	128	28 190 251 512 661 810					
GSM	Voice	3.55	3.55	3.55	3.55	3.55	3.55	
GSIVI	EDGE	3.77	3.76	3.75	3.78	3.76	3.75	

Table 7-3 UMTS Modulation Interference Factors¹

	•									
N/A	Mode		UMTS V		UMTS IV			UMTS II		
IVIC	ode	4132	4183	4233	1312	1412	1513	9262	9400	9538
	12.2 kbps RMC	-24.48	-23.87	-24.57	-24.79	-24.65	-24.12	-24.47	-24.68	-24.71
UMTS	12.2 kbps AMR	-25.00	-24.26	-24.95	-24.67	-24.89	-24.78	-24.80	-24.34	-24.85
	HSUPA Subtest1	-21.94	-23.49	-20.80	-19.05	-23.36	-20.37	-19.61	-20.22	-21.10

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

FCC ID: A3LSMA426U	PCTEST: Front to be port of a removed	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 10 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 18 of 103

© 2021 PCTEST **REV 3.5.M**

Table 7-4 LTE FDD Modulation Interference Factors^{1,2}

	LILI DD Modula		modulation	11110110101100	. 401010	1	
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
71	680.5	133297	20	16QAM	1	0	-9.68
12	707.5	23095	10	16QAM	1	0	-10.79
13	782.0	23230	10	16QAM	1	0	-10.06
14	793.0	23330	10	16QAM	1	0	-10.50
26	831.5	26865	15	16QAM	1	0	-9.98
5	836.5	20525	10	16QAM	1	0	-9.94
66	1745.0	132322	20	16QAM	1	0	-10.01
2	1880.0	18900	20	16QAM	1	0	-10.01
25	1882.5	26365	20	16QAM	1	0	-9.75
30	2310.0	27710	10	16QAM	1	0	-9.90
7	2535.0	21100	20	16QAM	1	0	-9.64
7	2535.0	21100	20	64QAM	1	0	-9.29
7	2535.0	21100	20	QPSK	1	0	-14.90
7	2535.0	21100	20	64QAM	1	50	-10.05
7	2535.0	21100	20	64QAM	1	99	-9.30
7	2535.0	21100	20	64QAM	50	0	-16.05
7	2535.0	21100	20	64QAM	100	0	-17.01
7	2535.0	21100	15	64QAM	1	0	-9.45
7	2535.0	21100	10	64QAM	1	0	-9.45
7	2535.0	21100	20	64QAM	1	0	-9.75
7	2510.0	20850	20	64QAM	1	0	-9.66
7	2560.0	21350	20	64QAM	1	0	-9.30

Table 7-5 LTE FDD Uplink Carrier Aggregation Modulation Interference Factor^{1,3}

				PCC							SCC				
Combination	PCC Band	PCC Bandwidth [MHz]	PCC (UL) Channel	PCC (UL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]	SCC (UL) Channel	SCC (UL) Frequency [MHz]	Modulation	SCC UL# RB	SCC UL RB Offset	MIF (dB)
CA_5B	LTE B5	10	20525	836.5	16QAM	1	0	LTE B5	5	20453	829.3	16QAM	1	24	-11.32
CA_66B	LTE B66	10	132322	1745.0	16QAM	1	0	LTE B66	10	132223	1735.1	16QAM	1	49	-11.04
CA_66C	LTE B66	20	132322	1745.0	16QAM	1	0	LTE B66	20	132124	1725.2	16QAM	1	99	-11.17

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 10 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 19 of 103

² Note: All FDD LTE bands were found to have substantially similar MIF values given similar RB, BW, and modulation configurations.

³ Note: LTE FDD ULCA was evaluated to ensure LTE FDD standalone was the worst-case scenario. The configurations in Table 7-5 were determined from Table 7-4 and satisfy the configuration requirements as defined in 3GPP 36.101.

Table 7-6 LTE TDD B41 Power Class 3 Modulation Interference Factors^{1,2}

LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
41	2593.0	40620	20	16QAM	1	0	1.40
41	2593.0	40620	20	QPSK	1	0	1.40
41	2593.0	40620	20	64QAM	1	0	1.46
41	2593.0	40620	20	64QAM	1	50	1.48
41	2593.0	40620	20	64QAM	1	99	1.47
41	2593.0	40620	20	64QAM	50	0	1.29
41	2593.0	40620	20	64QAM	100	0	1.29
41	2593.0	40620	15	64QAM	1	36	1.52
41	2593.0	40620	10	64QAM	1	25	1.51
41	2593.0	40620	5	64QAM	1	12	1.33
41	2506.0	39750	15	64QAM	1	36	1.50
41	2549.5	40185	15	64QAM	1	36	1.44
41	2636.5	41055	15	64QAM	1	36	1.43
41	2680.0	41490	15	64QAM	1	36	1.42

Table 7-7 LTE TDD B41 Power Class 2 Modulation Interference Factors^{1,3}

LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
41	2593.0	40620	20	16QAM	1	0	-1.56
41	2593.0	40620	20	QPSK	1	0	-1.62
41	2593.0	40620	20	64QAM	1	0	-1.62
41	2593.0	40620	20	16QAM	1	50	-1.65
41	2593.0	40620	20	16QAM	1	99	-1.57
41	2593.0	40620	20	16QAM	50	0	-1.68
41	2593.0	40620	20	16QAM	100	0	-1.69
41	2593.0	40620	15	16QAM	1	0	-1.41
41	2593.0	40620	10	16QAM	1	0	-1.39
41	2593.0	40620	5	16QAM	1	0	-1.54
41	2506.0	39750	10	16QAM	1	0	-1.57
41	2549.5	40185	10	16QAM	1	0	-1.65
41	2636.5	41055	10	16QAM	1	0	-1.42
41	2680.0	41490	10	16QAM	1	0	-1.57

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

³ Note: LTE TDD Power Class 2 MIFs were taken using UL-DL Configuration 1. More information about the chosen UL-DL Configuration can be found in Section 10.

FCC ID: A3LSMA426U	PCTEST: Road to be post of \$ sensors	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 20 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 20 01 103

² Note: LTE TDD Power Class 3 MIFs were taken using UL-DL Configuration 2. More information about the chosen UL-DL Configuration can be found in Section 10.

Table 7-8LTE TDD B48 Modulation Interference Factors^{1,2}

LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
48	3625.0	55990	20	16QAM	1	0	1.40
48	3625.0	55990	20	QPSK	1	0	1.44
48	3625.0	55990	20	64QAM	1	0	1.42
48	3625.0	55990	20	QPSK	1	50	1.44
48	3625.0	55990	20	QPSK	1	99	1.44
48	3625.0	55990	20	QPSK	50	0	1.42
48	3625.0	55990	20	QPSK	100	0	1.41
48	3625.0	55990	15	QPSK	1	0	1.41
48	3625.0	55990	10	QPSK	1	0	1.45
48	3625.0	55990	5	QPSK	1	0	1.43
48	3555.0	55290	10	QPSK	1	0	1.42
48	3601.7	55757	10	QPSK	1	0	1.44
48	3648.3	56223	10	QPSK	1	0	1.42
48	3695.0	56690	10	QPSK	1	0	1.43

Table 7-9LTE TDD Uplink Carrier Aggregation Modulation Interference Factor^{1,3}

				• P	. • • • • • • • • • • • • • • • • • • •	· · · · · · · · · · · · · · · · · · ·	- 5								
				PCC				SCC							
Combination	PCC Band	PCC Bandwidth [MHz]	PCC (UL/DL) Channel	PCC (UL/DL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]	SCC (UL/DL) Channel	SCC (UL/DL) Frequency [MHz]		SCC UL# RB	SCC UL RB Offset	MIF (dB)
CA_41C (PC3)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	1.47
CA_41C (PC2)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	-1.55

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

FCC ID: A3LSMA426U	PCTEST: Froud to be port of the security	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 21 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 21 of 103

² Note: LTE TDD Power Class 3 MIFs were taken using UL-DL Configuration 2. More information about the chosen UL-DL Configuration can be found in Section 10.

³ Note: LTE TDD ULCA was evaluated to ensure LTE TDD standalone was the worst-case scenario. The configurations in Table 7-9 were determined from Tables 7-6 to 7-7 and satisfy the configuration requirements as defined in 3GPP 36.101. These MIFs were evaluated with UL-DL Configuration 2 for Power Class 3 LTE TDD and UL-DL Configuration 1 for Power Class 2 LTE TDD.

Table 7-10
NR FDD Modulation Interference Factors¹

		14141	ואסטעו	ation inten	crenee r a	0.010		
NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n71	680.5	136100	20	DFT-s-OFDM	16QAM	1	1	-12.26
n5	836.5	167300	20	DFT-s-OFDM	16QAM	1	1	-12.43
n66	1745.0	349000	20	DFT-s-OFDM	16QAM	1	1	-12.46
n25	1882.5	376500	20	DFT-s-OFDM	16QAM	1	1	-10.83
n25	1882.5	376500	20	DFT-s-OFDM	π/2-BPSK	1	1	-16.81
n25	1882.5	376500	20	DFT-s-OFDM	QPSK	1	1	-15.87
n25	1882.5	376500	20	DFT-s-OFDM	64QAM	1	1	-12.12
n25	1882.5	376500	20	DFT-s-OFDM	256QAM	1	1	-8.13
n25	1882.5	376500	20	CP-OFDM	QPSK	1	1	-13.72
n25	1882.5	376500	20	CP-OFDM	16QAM	1	1	-10.16
n25	1882.5	376500	20	CP-OFDM	64QAM	1	1	-10.67
n25	1882.5	376500	20	CP-OFDM	256QAM	1	1	-10.87
n25	1882.5	376500	20	DFT-s-OFDM	256QAM	1	53	-8.16
n25	1882.5	376500	20	DFT-s-OFDM	256QAM	1	104	-9.28
n25	1882.5	376500	20	DFT-s-OFDM	256QAM	50	0	-16.75
n25	1882.5	376500	20	DFT-s-OFDM	256QAM	100	0	-16.37
n25	1882.5	376500	15	DFT-s-OFDM	256QAM	1	1	-8.88
n25	1882.5	376500	10	DFT-s-OFDM	256QAM	1	1	-9.22
n25	1882.5	376500	5	DFT-s-OFDM	256QAM	1	1	-9.32
n25	1860.0	372000	20	DFT-s-OFDM	256QAM	1	1	-8.97
n25	1905.0	381000	20	DFT-s-OFDM	256QAM	1	1	-9.32

Table 7-11NR TDD – n41 Modulation Interference Factors¹

NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	1	1	1.40
n41	2593.0	518598	100	DFT-s-OFDM	QPSK	1	1	1.36
n41	2593.0	518598	100	DFT-s-OFDM	16QAM	1	1	1.33
n41	2593.0	518598	100	DFT-s-OFDM	64QAM	1	1	1.33
n41	2593.0	518598	100	DFT-s-OFDM	256QAM	1	1	1.39
n41	2593.0	518598	100	CP-OFDM	QPSK	1	1	1.28
n41	2593.0	518598	100	CP-OFDM	16QAM	1	1	1.22
n41	2593.0	518598	100	CP-OFDM	64QAM	1	1	1.30
n41	2593.0	518598	100	CP-OFDM	256QAM	1	1	1.19
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	1	137	1.39
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	1	271	1.39
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	135	0	1.41
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	270	0	1.40
n41	2593.0	518598	80	DFT-s-OFDM	π/2-BPSK	108	0	1.40
n41	2593.0	518598	60	DFT-s-OFDM	π/2-BPSK	81	0	1.40
n41	2593.0	518598	40	DFT-s-OFDM	π/2-BPSK	50	0	1.40
n41	2593.0	518598	20	DFT-s-OFDM	π/2-BPSK	25	0	1.39
n41	2546.0	509202	100	DFT-s-OFDM	π/2-BPSK	135	0	1.43
n41	2569.5	513900	100	DFT-s-OFDM	π/2-BPSK	135	0	1.40
n41	2616.5	523302	100	DFT-s-OFDM	π/2-BPSK	135	0	1.41
n41	2640.0	528000	100	DFT-s-OFDM	π/2-BPSK	135	0	1.39

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

				0
FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 22 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 22 01 103

Table 7-12NR TDD – n77 Modulation Interference Factors¹

NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n77	3750.0	650000	100	DFT-s-OFDM	π/2-BPSK	1	1	1.37
n77	3750.0	650000	100	DFT-s-OFDM	QPSK	1	1	1.34
n77	3750.0	650000	100	DFT-s-OFDM	16QAM	1	1	1.34
n77	3750.0	650000	100	DFT-s-OFDM	64QAM	1	1	1.40
n77	3750.0	650000	100	DFT-s-OFDM	256QAM	1	1	1.35
n77	3750.0	650000	100	CP-OFDM	16QAM	1	1	1.27
n77	3750.0	650000	100	CP-OFDM	QPSK	1	1	1.15
n77	3750.0	650000	100	CP-OFDM	64QAM	1	1	1.30
n77	3750.0	650000	100	CP-OFDM	256QAM	1	1	1.25
n77	3750.0	650000	100	DFT-s-OFDM	64QAM	1	137	1.45
n77	3750.0	650000	100	DFT-s-OFDM	64QAM	1	271	1.42
n77	3750.0	650000	100	DFT-s-OFDM	64QAM	135	0	1.36
n77	3750.0	650000	100	DFT-s-OFDM	64QAM	270	0	1.35
n77	3750.0	650000	90	DFT-s-OFDM	64QAM	1	123	1.42
n77	3750.0	650000	80	DFT-s-OFDM	64QAM	1	109	1.43
n77	3750.0	650000	60	DFT-s-OFDM	64QAM	1	81	1.42
n77	3750.0	650000	50	DFT-s-OFDM	64QAM	1	67	1.42
n77	3750.0	650000	40	DFT-s-OFDM	64QAM	1	53	1.42
n77	3750.0	650000	20	DFT-s-OFDM	64QAM	1	26	1.44
n77	3795.0	653000	100	DFT-s-OFDM	64QAM	1	137	1.42
n77	3840.0	656000	100	DFT-s-OFDM	64QAM	1	137	1.42
n77	3885.0	659000	100	DFT-s-OFDM	64QAM	1	137	1.42
n77	3930.0	662000	100	DFT-s-OFDM	64QAM	1	137	1.42

Table 7-13

802.11b (2.4GHz, SISO) Modulation Interference Factors^{1,2}

	802.1	802.11b MIF Measurements [dB]								
Mode		Data Rate [Mbps]								
	1	1 2 5.5 11								
802.11b	-9.10	-9.10 -13.59 -11.27 -10.52								

Table 7-14

802.11g (2.4GHz, SISO) Modulation Interference Factors^{1,2}

	302.11g (2.161.2, 616.6) installation interference i deters										
	802.11g MIF Measurements [dB]										
Mode		Data Rate [Mbps]									
	6	6 9 12 18 24 36 48 54									
802.11g	-11.52	-10.81	-10.37	-9.66	-9.20	-9.56	-10.02	-10.25			

Table 7-15

802.11n (2.4GHz, SISO) Modulation Interference Factors^{1,2}

	002.1	··· (=: · • ·	<u>, </u>	modalatic	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	enee i ae					
	802.11n (2.4GHz) MIF Measurements [dB]										
Mode		MCS Index									
	0	0 1 2 3 4 5 6 7									
802.11n	-11.74	-10.63	-9.68	-9.41	-9.56	-9.99	-10.22	-10.42			

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

² Note: WIFI MIF values were found to be independent of the transmit channel.

FCC ID: A3LSMA426U	POTEST: Possed to the post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 22 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 23 of 103

Table 7-16802.11a (5GHz. 20MHz BW. SISO) Modulation Interference Factors^{1,2}

	662. Tra (OCT)2, 2011112 BVV, CICO) Middlation interference i actors											
		802.11a MIF Measurements [dB]										
Mode		Data Rate [Mbps]										
	6	6 9 12 18 24 36 48 54										
802.11a	-11.74	-10.99	-10.52	-9.78	-9.35	-9.62	-9.94	-10.26				

Table 7-17

802.11n (5GHz, 20MHz BW, SISO) Modulation Interference Factors^{1,2}

20MHz BW 802.11n (5GHz) MIF Measurements [dB]											
Mode		MCS Index									
	0	0 1 2 3 4 5 6 7									
802.11n	-11.99	11.99 -10.85 -9.87 -9.58 -9.74 -10.14 -10.36 -10.68									

Table 7-18

802.11ac (5GHz, 20MHz BW, SISO) Modulation Interference Factors^{1,2}

	20MHz BW 802.11ac (5GHz) MIF Measurements [dB]									
Mode		MCS Index								
	0	0 1 2 3 4 5 6 7 8								
802.11ac	-11.84	-10.71	-9.78	-9.45	-9.66	-9.99	-10.25	-10.57	-10.82	

Table 7-19

802.11n (5GHz, 40MHz BW, SISO) Modulation Interference Factors^{1,2}

	•	40MHz BW 802.11n (5GHz) MIF Measurements [dB]										
Mode		MCS Index										
	0	0 1 2 3 4 5 6 7										
802.11n	-9.69	-8.92	-9.17	-9.66	-10.65	-10.96	-11.66	-11.71				

Table 7-20

802.11ac (5GHz, 40MHz BW, SISO) Modulation Interference Factors^{1,2}

		40MHz BW 802.11ac (5GHz) MIF Measurements [dB]										
Mode		MCS Index										
	0	0 1 2 3 4 5 6 7 8 9										
802.11ac	-9.64	-8.80	-9.15	-9.58	-10.64	-11.27	-11.47	-11.47	N/A	-11.66		

Table 7-21

802.11ac (5GHz, 80MHz BW, SISO) Modulation Interference Factors^{1,2}

	80MHz BW 802.11ac (5GHz) MIF Measurements [dB]										
Mode		MCS Index									
	0	0 1 2 3 4 5 6 7 8 9									
802.11ac	-9.28	-9.89	-10.96	-11.55	-11.08	-13.45	-13.66	-13.80	-14.34	-14.37	

¹ Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

FCC ID: A3LSMA426U	PCTEST Proceed to the post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 24 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 24 01 103

² Note: WIFI MIF values were found to be independent of the transmit channel.

8. RF CONDUCTED POWER MEASUREMENTS

I. Procedures Used to Establish RF Signal for HAC Testing

The handset was configured to transmit the required air interface in a shielded chamber. Measurements were taken with a fully charged battery.

II. HAC Measurement Conditions

Output Power Verification

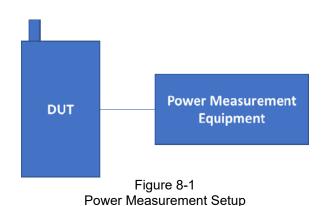
Maximum output power is verified on the High, Middle and Low channels for all applicable air interfaces for which full testing scans are required. Modes which are exempted from full testing according to Section 9 of this report have only their conducted power targets listed below, not measured values. See Table 8-1 for air interface specific settings of transmit power parameters. See Table 9-1 for more information regarding which modes required full testing and had conducted power measurements taken.

Table 8-1
Power Control Parameters and Settings by Air Interface

Air Interface:	Parameter Name:	Parameter Set To:
CDMA	Power Control Bits	"All Up"
GSM	PCL	GSM850: "5"; GSM1900: "0"
UMTS	TPC	"All 1's"
LTE	TPC	"Max Power"
NR	PLS	Mfr Specified
WIFI	PLS	Mfr Specified

III. Setup Used to Measure RF Conducted Powers

The general setup for conducted power is shown in Figure 8-1 below. The power measurement equipment could be a base station simulator, signal analyzer, or power meter depending on the applicable air interface.



FCC ID: A3LSMA426U	PCTEST Proceed to the post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 25 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 25 01 105

IV. CDMA Target Powers

Table 8-2 **CDMA Conducted Power Targets**

ODMA Conducted I ower rangets				
		Modulated Average Output Power		
Band Class		(in d	Bm)	
		1x-RTT	EVDO Rev. A	
BC10	Max allowed power	26.0	25.0	
PC10	Nominal	25.0	24.0	
BC0	Max allowed power	26.0	25.0	
ВСО	Nominal	25.0	24.0	
BC1	Max allowed power	26.0	25.0	
BCI	Nominal	25.0	24.0	

V. GSM Target Powers

Table 8-3 **GSM Conducted Power Targets**

Goin Conadoted Fortor Fargote				
		Voice	Data	
Band		(in dBm)	(in dBm)	
		1 TX Slot	1 TX Slots	
GSM/GPRS/EDGE 850	Max allowed power	33.5	27.5	
GSIVI/GPRS/EDGE 650	Nominal	32.5	26.5	
GSM/GPRS/EDGE 1900	Max allowed power	30.5	26.5	
GSIVI/GPRS/EDGE 1900	Nominal	29.5	25.5	

VI. UMTS Target Powers

Table 8-4 **UMTS Conducted Power Targets**

		Modulated Average Output Power (in dBm)			wer
Band		3GPP WCDMA Rel 99	3GPP HSDPA Rel 5	3GPP HSUPA Rel 6	3GPP DC-HSDPA Rel 8
Band 5	Max allowed power	25.0	24.0	24.0	24.0
Ballu 5	Nominal	24.0	23.0	23.0	23.0
Band 4	Max allowed power	25.0	24.0	24.0	24.0
ballu 4	Nominal	24.0	23.0	23.0	23.0
Donal 2	Max allowed power	25.0	24.0	24.0	24.0
Band 2	Nominal	24.0	23.0	23.0	23.0

FCC ID: A3LSMA426U	PCTEST Proact to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 26 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 20 01 103

VII. LTE FDD Target Powers

Table 8-5 **LTE FDD Conducted Power Targets**

Mode / Band Modulated Average Output Power (in dBm) LTE FDD Band 71 Max allowed power 25.5 Nominal 24.5 Max allowed power 24.0 Nominal 23.0 Max allowed power 24.0 Nominal 23.0 Max allowed power 24.0 Nominal 23.0 Max allowed power 25.5 Nominal 24.5 Nominal 23.0 LTE FDD Band 5 Max allowed power 24.0 Nominal 23.0 Max allowed power 25.0 Nominal 24.0 Nominal 23.0 LTE FDD Band 66 Max allowed power 24.0 Nominal 23.5 Nominal 23.5 LTE FDD Band 25 Max allowed power 24.0 Nominal 23.0 Max allowed power 24.5 Nominal 23.0 Max allowed power 24.5 Nominal 23.0 Max allowed power 24.5 Nominal 23.5 Max allowed power 24.5 Nominal 23.5 Max allowed power 24.0 Nominal 23.0 Max allowed power 24.0 Nominal 23.0 Max allowed power 24.0 Nominal 23.0 Nominal 23.0	LILIDO	onducted Fower i	argets
Nominal 24.5	Mode / Band		Average Output
Nominal 24.5	LTE EDD Band 71	Max allowed power	25.5
Nominal 23.0	LILIDD Ballu 71	Nominal	24.5
Nominal 23.0	LTE EDD Band 12	Max allowed power	24.0
Nominal 23.0	LTE FDD Ballu 12	Nominal	23.0
Nominal 23.0	LTE EDD Band 12	Max allowed power	24.0
Nominal 24.5	LIE FDD Ballu 13	Nominal	23.0
Nominal 24.5	LTE EDD Band 14	Max allowed power	25.5
Nominal 23.0 Max allowed power 25.0 Nominal 24.0 Max allowed power 24.0 Max allowed power 24.0 Mominal 23.0 Max allowed power 24.5 Mominal 23.5 Max allowed power 24.0 Max allowed power 24.5 Nominal 23.5 Max allowed power 24.0 Mominal 23.0 Max allowed power 24.5 Mominal 23.0 Max allowed power 24.5 Nominal 23.5 Max allowed power 24.5 Nominal 23.5 Max allowed power 23.0 Max allowed power 23.0 Max allowed power 23.0 Max allowed power 24.0 M	LIE FDD Ballu 14	Nominal	24.5
Nominal 23.0	LTE CDD Band F	Max allowed power	24.0
Nominal 24.0	LIE FUU Ballu 5	Nominal	23.0
Nominal 24.0	LTE EDD Band 26	Max allowed power	25.0
Nominal 23.0	LTE FDD Ballu 20	Nominal	24.0
Nominal 23.0	LTE CDD Band 4	Max allowed power	24.0
Nominal 23.5	LIE FDD Ballu 4	Nominal	23.0
Nominal 23.5 LTE FDD Band 2 Max allowed power 24.0 Nominal 23.0 LTE FDD Band 25 Max allowed power 24.5 Nominal 23.5 LTE FDD Band 30 Max allowed power 23.0 LTE FDD Band 7 Max allowed power 24.0 LTE FDD	LTE EDD Band 66	Max allowed power	24.5
Nominal 23.0	LIE FDD Ballu 00	Nominal	23.5
Nominal 23.0	LTE EDD Pand 2	Max allowed power	24.0
Nominal 23.5	LTE FDD Ballu 2	Nominal	23.0
Nominal 23.5	LTE EDD Band 25	Max allowed power	24.5
Nominal 22.0	LIE FUU Ballu 23	Nominal	23.5
Nominal 22.0 LTE FDD Band 7 Max allowed power 24.0	LTE EDD Band 20	Max allowed power	23.0
LIEFDD Band /	LIE FDD Ballu 30	Nominal	22.0
Nominal 23.0	I TE EDD Band 7	Max allowed power	24.0
	LILI DD Ballu /	Nominal	23.0

Table 8-6 LTE FDD Uplink Carrier Aggregation Conducted Power Targets

Mode / Band		Modulated Average Output Power (in dBm)
LTE FDD Band 5	Max allowed power	24.0
LIE FDD Ballu 3	Nominal	23.0
LTE FDD Band 66	Max allowed power	24.5
LIE FDD Balla 00	Nominal	23.5

FCC ID: A3LSMA426U	POTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 27 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 27 of 103
© 2021 PCTEST				REV 3.5.M

VIII. LTE TDD Target Powers

Table 8-7 **LTE TDD Conducted Power Targets**

Mode / Band		Modulated Average Output Power (in dBm)
LTE TDD Band 48	Max allowed power	23.0
LTE TOO Ballu 46	Nominal	22.0
LTE TDD Band 41 (PC3)	Max allowed power	24.5
LIE IDD Ballu 41 (PC3)	Nominal	23.5
LTE TDD Band 41 (PC2)	Max allowed power	27.0
LIL IDD Ballu 41 (PC2)	Nominal	26.0

Table 8-8 LTE TDD Uplink Carrier Aggregation Conducted Power Targets

Mode / Band		Modulated Average Output Power (in dBm)
LTE TDD Band 41 (PC3)	Max allowed power	24.5
LTE TOO Ballu 41 (PCS)	Nominal	23.5
LTE TDD Band 41 (PC2)	Max allowed power	27.0
LIE IDD Ballu 41 (PC2)	Nominal	26.0

FCC ID: A3LSMA426U	PCTEST Proact to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 28 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 26 01 103

IX. NR FDD Target Powers

Table 8-9 NR FDD Conducted Power Targets

	Titt 1 DD Golladotod 1 Gwol Taligoto									
Mode / Band		Modulated Average Output Power (in dBm)								
NR FDD n2	Max allowed power	25.0								
INK FDD 112	Nominal	24.0								
NR FDD n5	Max allowed power	25.0								
כוו טטר אאו	Nominal	24.0								
NR FDD n66	Max allowed power	25.0								
INK FDD 1100	Nominal	24.0								
NR FDD n25	Max allowed power	25.0								
מאון באט וואס	Nominal	24.0								
NR FDD n71	Max allowed power	25.0								
NK FUU N/1	Nominal	24.0								

X. NR TDD Target Powers

Table 8-10 NR TDD Conducted Power Targets

1111 1 = = 1 1111 1111 1111 1111 1111 1111 1111 1111								
Mode / Band		Modulated Average Output Power (in dBm)						
NR TDD n41	Max allowed power	24.0						
NK 100 1141	Nominal	23.0						
NR TDD n77	Max allowed power	24.0						
/ זוו טטו אוי	Nominal	23.0						

FCC ID: A3LSMA426U	PCTEST Proact to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 29 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 29 01 103

XI. WIFI Target Powers (SISO)

Table 8-11 IEEE 2.4GHz 802.11b/g/n Reduced Average RF Power Targets¹

<u> </u>	nie dozini brgini redudodu i tvorugo i tr. i dwor											
Mode	Band	IEEE 802.11 (in dBm)										
Wode	Danu	b		g	n							
	mum / al Power	Max	Nom.	. Max		Nom.	Max	Nom.				
2.4	2.45	16.0	15.0	16.0	0	15.0	16.0	15.0				
GHz WIFI	GHz	ch. 13: 14.0	13.0	ch. 12: ch. 13:			ch. 12: 14.0 ch. 13: 11.5					

Table 8-12 IEEE 5GHz 802.11a/n/ac Reduced Average RF Power Targets¹

OI IZ O	JZ. 1 1 a/1	mac ne	uuce	eu Avera	age i	VI I OW	<u> </u>	
Mode	Pand		IEEE 802.11 (in dBm)					
iviode	Band	а		n		ac		
	/ Nominal wer	Max	Nom.	Max	Nom.	Max	Nom.	
	5200 MHz	11.0	10.0	11.0	10.0	11.0	10.0	
5 GHz WIFI	5300 MHz	11.0	10.0	11.0	10.0	11.0	10.0	
(20MHz BW)	5500 MHz	11.0	10.0	11.0	10.0	11.0	10.0	
,	5800 MHz	11.0	10.0	11.0	10.0	11.0	10.0	
	5200 MHz			11.0	10.0	11.0	10.0	
5 GHz WIFI	5300 MHz			11.0	10.0	11.0	10.0	
(40MHz BW)	5500 MHz			11.0	10.0	11.0	10.0	
,	5800 MHz			11.0	10.0	10.0	10.0	

Table 8-13 IEEE 5GHz 802.11ac Maximum Average RF Power Targets

<u> </u>	<u> </u>	ao iliaxii			<u> </u>					
Mode	Dand	IEEE 802.11 (in dBm)								
iviode	Band	а		n		ac				
	/ Nominal wer	Max	Nom.	Max	Nom.	Max	Nom.			
	5200 MHz					11.0	10.0			
5 GHz WIFI	5300 MHz					11.0	10.0			
(80MHz BW)	5500 MHz					11.0	10.0			
,	5800 MHz					11.0	10.0			

¹ Note: This device utilizes independent power reduction mechanisms for the WIFI transmitter in all WIFI modes for held-to-ear scenarios.

FCC ID: A3LSMA426U	PCTEST Proceed to the post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 30 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage 30 01 103

JUSTIFICATION OF HELD TO EAR MODES TESTED 9.

I. Analysis of RF Air Interface Technologies

An analysis was performed, following the guidance of §4.3 and §4.4 of the ANSI standard, of the RF air interface technologies being evaluated. The factors that will affect the RF interference potential were evaluated, and the worst-case operating modes were identified and used in the evaluation. A WD's interference potential is a function both of the WD's average near-field field strength and of the signal's audio-frequency amplitude modulation characteristics. Per §4.4, RF air interface technologies that have low power have been found to produce sufficiently low RF interference potential, so it is possible to exempt them from the product testing specified in Clause 5 of the ANSI standard. An RF air interface technology of a device is exempt from testing when its average antenna input power plus its MIF is ≤17dBm for all of its operating modes. RF air interface technologies exempted from testing in this manner are automatically assigned an M4 rating to be used in determining the overall rating for the WD.

The worst-case MIF plus the worst-case average antenna input power for all modes are investigated below to determine the testing requirements for this device.

II. Individual Mode Evaluations

Table 9-1 Max Power + MIF calculations for Low Power Exemptions

Air Interface	Maximum Average Power (dBm)	Worst Case MIF (dB)	Total (Power + MIF, dB)	C63.19 Testing Required
CDMA - Full Frame Rate	26.00	-19.92	6.08	No
CDMA - 1/8 th Frame Rate	16.97*	3.11	20.08	Yes
CDMA - EvDO	25.00	-19.20	5.80	No
GSM - GSM850	24.31*	3.55	27.86	Yes
GSM - GSM1900	21.31*	3.55	24.86	Yes
GSM - EDGE850	18.31*	3.77	22.08	Yes**
GSM - EDGE1900	17.31*	3.78	21.09	Yes**
UMTS - RMC	25.00	-23.87	1.13	No
UMTS - AMR	25.00	-24.26	0.74	No
UMTS - HSPA	24.00	-19.05	4.95	No
LTE FDD	25.50	-9.29	16.21	No
LTE FDD - Uplink Carrier Aggregation	24.50	-11.04	13.46	No
LTE TDD - Band 41 (PC3)	17.81*	1.52	19.33	Yes
LTE TDD - Band 41 (PC2)	23.16*	-1.39	21.77	Yes
LTE TDD - Band 48	16.31*	1.45	17.76	Yes
LTE TDD - Uplink Carrier Aggregation	23.16*	-1.55	21.61	Yes***
NR FDD	25.00	-8.13	16.87	No
NR TDD - n41	18.98*	1.43	20.41	Yes
NR TDD - n77	17.98*	1.45	19.43	Yes
WIFI - 2.4GHz	16.00	-9.10	6.90	No
WIFI - 5GHz	11.00	-8.80	2.20	No

^{*} Note: ANSI C63.19-2011 Sec. 4.4 Footnote 20 indicates the use of a long averaging time for measuring the antenna input power when using this method of exclusion. Therefore, the frame averaged power was calculated for these modes in this investigation.

^{***} Note: LTE TDD Uplink Carrier Aggregation data modes were considered but not tested as LTE standalone modes were found to be the worst-case modes for the LTE air interface.

FCC ID: A3LSMA426U	PCTEST: Front to be post of @ reserved	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 24 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 31 of 103

^{**} Note: EDGE data modes were considered but not tested as GSM voice modes were found to be the worst-case modes for the GSM air interface.

III. Low-Power Exemption Conclusions

Per ANSI C63.19-2011, RF Emissions testing for this device is required only for GSM/CDMA 1/8th Frame Rate voice modes as well as LTE TDD (Power Class 3 and Power Class 2) and NR TDD data modes. All other air interfaces are exempt.

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 22 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 32 of 103
© 2021 PCTEST	•	•		REV 3.5.M

10. LTE TDD UPLINK-DOWNLINK CONFIGURATION

I. Uplink-Downlink Configuration Additional Testing

Additional testing was performed on each supported power class for LTE TDD to determine the worst-case Uplink-Downlink configuration for RFE testing.

Per 3GPP TS 36.211, the total frame length for each TDD radio frame of length T_f = 307200 · T_s = 10 ms, where T_s is a number of time units equal to 1/(15000 x 2048) seconds. Additionally, each radio frame consists of 10 subframes, each of length $30720 \cdot T_s$ = 1 ms, and subframes can be designated as uplink (U), downlink (D), or special subframe (S), depending on the Uplink-Downlink configuration as indicated in Table 4.2-2 of 3GPP TS 36.211. In the transmission duty factor calculation, the special subframe configuration with the shortest UpPTS duration within the special subframe is used and will be applied for measurement. From 3GPP TS 36.211 Table 4.2-1, the shortest UpPTS is 2192 · Ts which occurs in the normal cyclic prefix and special subframe configuration 4.

See table below outlining the calculated transmission duty cycles for each Uplink-Downlink configuration:

Table 10-1Uplink-Downlink Configurations for Type 2 Frame Structures

Uplink-downlink configuration	Downlink-to-Uplink Switch-point periodicity		Subframe number							Calculated Transmission		
configuration	0	1	2	3	4	5	6	7	8	9	Duty Cycle (%)	
0	5 ms	D	S	U	U	U	D	S	U	U	U	61.4%
1	5 ms	D	S	U	U	D	D	S	U	U	D	41.4%
2	5 ms	D	S	U	D	D	D	S	U	D	D	21.4%
3	10 ms	D	S	U	U	U	D	D	D	D	D	30.7%
4	10 ms	D	S	U	U	D	D	D	D	D	D	20.7%
5	10 ms	D	S	U	D	D	D	D	D	D	D	10.7%
6	5 ms	D	S	U	U	U	D	S	U	U	D	51.4%

II. Power Class 3 Uplink-Downlink Configuration Additional Testing

LTE TDD was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 3, all configurations (0-6) are supported. The configuration which resulted in the worst-case emission was used for full testing. See Table 10-2 below for results. The configuration determined in the results below was used to measure the MIF values in Tables 7-6, 7-8 and 7-9.

Table 10-2LTE TDD Power Class 3 UL-DL Configuration Results

	Let The Tower Glass of GE be comparation recoined														
Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	eld Emissions														
	20	40620	0	16QAM	1	0	Acoustic	20.97	26.43	-3.23	23.20	35.00	-11.80	M4	1,2,3
	20	40620	1	16QAM	1	0	Acoustic	17.77	24.99	-1.55	23.44	35.00	-11.56	M4	1,2,3
	20	40620	2	16QAM	1	0	Acoustic	12.64	22.03	1.48	23.51	35.00	-11.49	M4	1,2,3
LTE TDD / Band 41	20	40620	3	16QAM	1	0	Acoustic	15.91	24.03	-1.49	22.54	35.00	-12.46	M4	1,2,3
	20	40620	4	16QAM	1	0	Acoustic	13.17	22.39	0.67	23.06	35.00	-11.94	M4	1,2,3
	20	40620	5	16QAM	1	0	Acoustic	9.61	19.65	3.46	23.11	35.00	-11.89	M4	1,2,4
	20	40620	6	16QAM	1	0	Acoustic	20.01	26.02	-2.54	23.48	35.00	-11.52	M4	1,2,3

FCC ID: A3LSMA426U	PCTEST: Froud to be port of the second	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 22 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 33 of 103

III. Power Class 2 Uplink-Downlink Configuration Additional Testing

LTE TDD was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 2, only configurations 1-5 are supported. The configuration which resulted in the worst-case emission was used for full testing. See Table 10-3 below for results. The configuration determined in the results below was used to measure the MIF values in Tables 7-7 and 7-9.

Table 10-3LTE TDD Power Class 2 UL-DL Configuration Results

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	-Field Emissions														
	20	40620	1	16QAM	1	0	Acoustic	24.14	27.65	-1.57	26.08	35.00	-8.92	M4	1,2,3
	20	40620	2	16QAM	1	0	Acoustic	16.81	24.51	1.52	26.03	35.00	-8.97	M4	1,2,3
LTE TDD / Band 41	20	40620	3	16QAM	1	0	Acoustic	20.24	26.12	-1.48	24.64	35.00	-10.36	M4	1,2,3
	20	40620	4	16QAM	1	0	Acoustic	16.97	24.59	0.72	25.31	35.00	-9.69	M4	1,2,3
	20	40620	5	16QAM	1	0	Acoustic	12.16	21.70	3.77	25.47	35.00	-9.53	M4	1,2,4

IV. Conclusion

Per the results above, UL-DL Configuration 2 was used for LTE TDD Power Class 3 and UL-DL Configuration 1 was used for LTE TDD Power Class 2 testing.

FCC ID: A3LSMA426U	POTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 24 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 34 of 103

11. OVERALL MEASUREMENT SUMMARY

FCC ID:	A3LSMA426U
S/N:	13433, 51730

I. E-FIELD EMISSIONS:

Table 11-1
HAC Data Summary for CDMA E-field

	HAC Data Sullillary for CDWA E-Heru														
Mode	Channel	RC/SO	Sample S/N	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5		
E-Field Emiss	ions														
_	564*	RC1/SO3	13433	Acoustic	24.82	21.56	26.67	3.10	29.77	45.00	-15.23	M4	1,4,7		
Cellular	1013	RC1/SO3	13433	Acoustic	24.94	19.89	25.97	3.11	29.08	45.00	-15.92	M4	1,4,7		
CDMA	384	RC1/SO3	13433	Acoustic	24.94	18.39	25.29	3.07	28.36	45.00	-16.64	M4	1,4,7		
	777	RC1/SO3	13433	Acoustic	24.65	20.76	26.34	3.06	29.40	45.00	-15.60	M4	1,4,7		
	25	RC1/SO3	13433	Acoustic	25.06	15.23	23.65	3.10	26.75	35.00	-8.25	M4	1,4,7		
PCS CDMA	600	RC1/SO3	13433	Acoustic	25.01	14.78	23.39	3.09	26.48	35.00	-8.52	M4	1,4,7		
	1175	RC1/SO3	13433	Acoustic	24.89	13.95	22.89	3.05	25.94	35.00	-9.06	M4	1.4.7		

^{*}Note: Cell. CDMA Ch. 564 is the Part 90S test channel.

Table 11-2
HAC Data Summary for GSM E-field

	TIAG Data Guillinary for Goin E-neid														
Mode	Channel	Sample S/N	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5			
E-Field Emission	eld Emissions														
	128	13433	Acoustic	33.01	44.40	32.95	3.55	36.50	45.00	-8.50	M4	1,2,4			
GSM850	190	13433	Acoustic	33.07	37.49	31.48	3.55	35.03	45.00	-9.97	M4	1,2,4			
	251	13433	Acoustic	32.68	36.90	31.34	3.55	34.89	45.00	-10.11	M4	1,2,4			
	512	13433	Acoustic	30.50	13.73	22.75	3.55	26.30	35.00	-8.70	M4	7,8,9			
GSM1900	661	13433	Acoustic	30.08	11.94	21.54	3.55	25.09	35.00	-9.91	M4	7,8,9			
	810	13433	Acoustic	30.18	11.56	21.26	3.55	24.81	35.00	-10.19	M4	7,8,9			

Table 11-3
HAC Data Summary for LTE TDD Band 41 (PC3) E-field

			1 1/	~~ i	Jaco	ı ou		aryio		ם טטו	allu T	1 (1 0	<i>)</i> L-110	iu			
Mode / Band	Bandwidth (MHz)	Channel	Sample S/N	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission																	
	15	39750	13433	2	64QAM	1	36	Acoustic	21.81	9.98	19.98	1.50	21.48	35.00	-13.52	M4	2,3,6
	15	40185	13433	2	64QAM	1	36	Acoustic	21.92	9.44	19.50	1.44	20.94	35.00	-14.06	M4	1,2,4
LTE TDD / Band 41 PC3	15	40620	13433	2	64QAM	1	36	Acoustic	21.89	12.43	21.89	1.52	23.41	35.00	-11.59	M4	1,2,3
Band 41 PC3	15	41055	13433	2	64QAM	1	36	Acoustic	21.28	10.08	20.07	1.43	21.50	35.00	-13.50	M4	1,2,3
	15	41490	13433	2	64QAM	1	36	Acoustic	21.58	8.52	18.61	1.42	20.03	35.00	-14.97	M4	1,2,4

FCC ID: A3LSMA426U	PCTEST* Road to be post of \$\infty\$ resources	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 25 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 35 of 103

Table 11-4 HAC Data Summary for LTE TDD Band 41 (PC2) E-field

								· · · · · · · · · · · · · · · · · · ·			 .	. (. –-	-, — …				
Mode / Band	Bandwidth (MHz)	Channel		UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons																
	10	39750	13433	1	16QAM	1	0	Acoustic	24.90	22.65	27.10	-1.57	25.53	35.00	-9.47	M4	2,3,6
	10	40185	13433	1	16QAM	1	0	Acoustic	25.69	17.03	24.62	-1.65	22.97	35.00	-12.03	M4	1,2,4
LTE TDD / Band 41 PC2	10	40620	13433	1	16QAM	1	0	Acoustic	25.27	23.61	27.46	-1.39	26.07	35.00	-8.93	M4	1,2,3
Band 41 PC2	10	41055	13433	1	16QAM	1	0	Acoustic	25.20	20.95	26.42	-1.42	25.00	35.00	-10.00	M4	1,2,3
	10	41490	13433	1	16QAM	1	0	Acoustic	24.32	17.30	24.76	-1.57	23.19	35.00	-11.81	M4	1,2,3

Table 11-5

HAC Data Summary for LTE TDD Band 48 E-field

Mode / Band	Bandwidth (MHz)	Channel		UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons																
	10	55290	51730	2	QPSK	1	0	Acoustic	21.70	25.60	28.16	1.42	29.58	35.00	-5.42	M4	2,3,6
	10	55757	51730	2	QPSK	1	0	Acoustic	21.35	23.86	27.55	1.44	28.99	35.00	-6.01	M4	2,3,6
LTE TDD /	10	55990	51730	2	QPSK	1	0	Acoustic	20.81	22.86	27.18	1.45	28.63	35.00	-6.37	M4	1,2,3
Band 48	10	56223	51730	2	QPSK	1	0	Acoustic	20.91	23.72	27.50	1.42	28.92	35.00	-6.08	M4	1,2,3
	10	56690	51730	2	QPSK	1	0	Acoustic	21.85	24.87	27.91	1.43	29.34	35.00	-5.66	M4	2,3,6
	10	55290	51730	2	QPSK	1	0	T-Coil	21.70	27.94	28.92	1.42	30.34	35.00	-4.66	M3	2,3,6

Table 11-6

HAC Data Summary for NR TDD n41 E-field

				1 17	70 D	utu	- ч	mina y	101 11		, ,,, ,						
Mode / Band	Bandwidth (MHz)	Channel	Sample S/N	Waveform	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons																
	100	509202	13433	DFT-s-OFDM	π/2-BPSK	135	0	Acoustic	22.18	11.64	21.32	1.43	22.75	35.00	-12.25	M4	1,2,3
	100	513900	13433	DFT-s-OFDM	π/2-BPSK	135	0	Acoustic	22.07	13.11	22.35	1.40	23.75	35.00	-11.25	M4	1,2,3
NR TDD / n41	100	518598	13433	DFT-s-OFDM	π/2-BPSK	135	0	Acoustic	22.17	12.56	21.98	1.41	23.39	35.00	-11.61	M4	1,2,3
	100	523302	13433	DFT-s-OFDM	π/2-BPSK	135	0	Acoustic	22.15	11.34	21.09	1.41	22.50	35.00	-12.50	M4	1,2,3
	100	528000	13433	DFT-s-OFDM	π/2-BPSK	135	0	Acoustic	22.27	14.02	22.93	1.39	24.32	35.00	-10.68	M4	1,2,3

Table 11-7

HAC Data Summary for NR TDD n77 E-field

Mode / Band	Bandwidth (MHz)	Channel	Sample S/N	Waveform	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons																
	100	653000	13433	DFT-s-OFDM	64QAM	1	137	Acoustic	20.57	19.37	25.74	1.42	27.16	35.00	-7.84	M4	2,3,6
	100	656000	13433	DFT-s-OFDM	64QAM	1	137	Acoustic	20.34	17.36	24.79	1.42	26.21	35.00	-8.79	M4	2,3,6
NR TDD / n77	100	650000	13433	DFT-s-OFDM	64QAM	1	137	Acoustic	20.16	21.63	26.70	1.45	28.15	35.00	-6.85	M4	2,3,6
	100	659000	13433	DFT-s-OFDM	64QAM	1	137	Acoustic	20.48	17.20	24.71	1.42	26.13	35.00	-8.87	M4	2,3,6
	100	662000	13433	DFT-s-OFDM	64QAM	1	137	Acoustic	20.36	16.17	24.17	1.42	25.59	35.00	-9.41	M4	2,3,6

FCC ID: A3LSMA426U	PCTEST* Proud to be post of ® resource	HAC (R	F EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
Filename:	Test Dates:	1	DUT Type:		Page 36 of 103	
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	F	Portable Handset		rage 30 of 103	

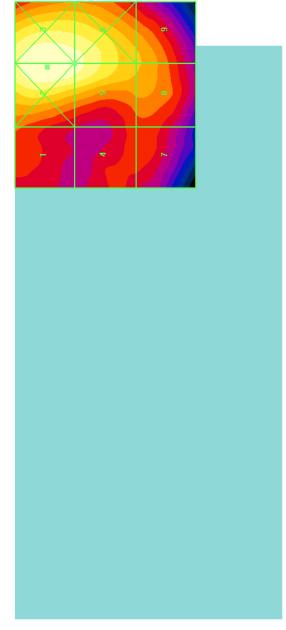


Figure 11-1
Sample E-field Scan Overlay
(T-Coil centered scan area pictured. Please see Test Setup Photographs for actual WD overlay and acoustic centered scan)

FCC ID: A3LSMA426U	PCTEST: Front to be post of @ reserved	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 27 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 37 of 103

© 2021 PCTEST

REV 3.5.M

FCC ID:	A3LSMA426U
S/N:	13433, 51730

II. Worst-case Configuration Evaluation

Table 11-8
Peak Reading 360° Probe Rotation at Azimuth axis

			-				,						-			
Mode	Bandwidth (MHz)	Channel	Sample S/N	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
Probe Rotation	at Worst-Case)														
LTE TDD / Band 48	10	55290	51730	2	QPSK	1	0	T-Coil	29.37	29.36	1.42	30.78	35.00	-4.22	M3	2,3,6

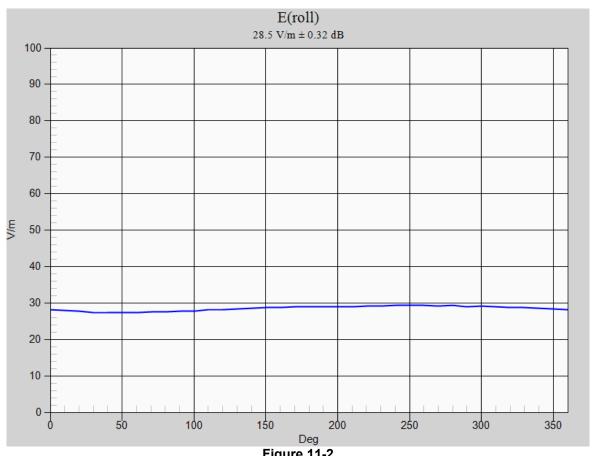


Figure 11-2
Worst-Case Probe Rotation about Azimuth axis

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 20 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 38 of 103

^{*} Note: Locations of probe rotation (with and without exclusions) are shown in Figure 11-1 denoted by the green square markers.

EQUIPMENT LIST 12.

Table 12-1 Equipment List

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	E4438C	ESG Vector Signal Generator	3/11/2019	Annual	3/11/2021	MY45090700
Agilent	N5182A	MXG Vector Signal Generator	2/19/2020	Annual	2/19/2021	MY47420651
Keysight Technologies	N9020A	MXA Signal Analyzer	3/26/2020	Annual	3/26/2021	MY56470202
Amplifier Research	15S1G6	Amplifier	N/A	CBT*	N/A	433978
Anritsu	MA24106A	USB Power Sensor	2/27/2020	Annual	2/27/2021	1244524
Anritsu	MA24106A	USB Power Sensor	6/8/2020	Annual	6/8/2021	1344555
Anritsu	MA2411B	Pulse Power Sensor	12/18/2020	Annual	12/18/2021	1027293
Anritsu	ML2496A	Power Meter	3/23/2020	Annual	3/23/2021	1351001
Control Company	4040	Therm./ Clock/ Humidity Monitor	3/6/2020	Biennial	3/6/2022	200170289
Mini-Circuits	NLP-1200+	Low Pass Filter DC to 1000 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	NLP-2950+	Low Pass Filter DC to 2700 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	BW-N20W5	Power Attenuator	N/A	CBT*	N/A	1226
Pasternack	PE2237-20	Bidirectional Coupler	N/A	CBT*	N/A	N/A
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	2/4/2020	Annual	2/4/2021	162125
Rohde & Schwarz	CMW500	Radio Communication Tester	5/21/2020	Annual	5/21/2021	128635
Seekonk	NC-100	Torque Wrench (8" lb)	8/4/2020	Biennial	8/4/2022	N/A
SPEAG	AIA	Audio Interference Analzyer	N/A	CBT*	N/A	1010
SPEAG	EF3DV3	Freespace E-field Probe	1/16/2019	Biennial	2/16/2021	4035
SPEAG	EF3DV3	Freespace E-field Probe	2/15/2021	Biennial	2/15/2023	4035
SPEAG	CD835V3	Freespace 835 MHz Dipole	3/14/2019	Biennial	3/14/2021	1190
SPEAG	CD1880V3	Freespace 1880 MHz Dipole	3/14/2019	Biennial	3/14/2021	1176
SPEAG	CD2600V3	Freespace 2600MHz Dipole	3/14/2019	Biennial	3/14/2021	1013
SPEAG	CD3500V3	Freespace 3500MHz Dipole	10/20/2020	Biennial	10/20/2022	1005
SPEAG	DAE4	Dasy Data Acquisition Electronics	2/12/2020	Annual	2/12/2021	665
SPEAG	DAE4	Dasy Data Acquisition Electronics	1/13/2021	Annual	1/13/2022	1530

Calibration traceable to the National Institute of Standards and Technology (NIST).

*Note: CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, attenuator, coupler or filter were connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 20 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 39 of 103

13. MEASUREMENT UNCERTAINTY

Table 13-1 Uncertainty Estimation Table

		Communication	ns Device Ne	ear-Field Me			
Uncertainty Component	Data	Data Type	Prob. Dist.	Divisor	Ci (E)	Unc. (dB)	Notes/Comments
	(dB)	,,				, ,	
Measurement System	0.50	- .		1.00		0.50	+ D (I - 00 ID
RF System Reflections	0.50	Tolerance	N	1.00	1	0.50	* Refl. < -20 dB
Field Probe Calibration	0.21	Tolerance	N	1.00	1	0.21	
Field Probe Isotropy	0.01	Tolerance	N	1.00	1	0.01	
Field Probe Frequency Response	0.135	Tolerance	N	1.00	1	0.14	
Field Probe Linearity	0.013	Tolerance	N	1.00	1	0.01	
Modulation Interference Factor	0.20	Tolerance	R	1.73	1	0.12	Applicable for M-rating testing
Boundary Effects	0.105	Accuracy	R	1.73	1	0.06	*
Probe Positioning Accuracy	0.20	Accuracy	R	1.73	1	0.12	*
Probe Positioner	0.050	Accuracy	R	1.73	1	0.03	*
Extrapolation/Interpolation	0.045	Tolerance	R	1.73	1	0.03	*
Resolution to 2mm error	0.21	Tolerance	N	1.00	1	0.21	
System Detection Limit	0.05	Tolerance	R	1.73	1	0.03	*
Readout Electronics	0.015	Tolerance	N	1.00	1	0.02	*
Integration Time	0.11	Tolerance	R	1.73	1	0.06	*
Response Time	0.033	Tolerance	R	1.73	1	0.02	*
Phantom Thickness	0.10	Tolerance	R	1.73	1	0.06	*
System Repeatability (Field x 2=power)	0.17	Tolerance	N	1.00	1	0.17	*
Test Sample Related							
Device Positioning Vertical	0.2	Tolerance	R	1.73	1	0.12	*
Device Positioning Lateral	0.045	Tolerance	R	1.73	1	0.03	*
Device Holder and Phantom	0.1	Tolerance	R	1.73	1	0.06	*
Power Drift	0.21	Tolerance	R	1.73	1	0.12	
Combined Standard Uncertainty (k=1)						0.66	16.3%
Expanded Uncertainty [95% confidence]						1.31	32.6%
Expanded Uncertainty [95% confidence]	on Field					0.66	16.3%

Notes:

- Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297. All
 equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81
 and NIST Tech Note 1297 and UKAS M3003.
- 2. * Uncertainty specifications from Schmidt & Partner Engineering AG (not site specific)

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid immunity tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 40 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 40 01 103

14. TEST DATA

See following Attached Pages for Test Data.

FCC ID: A3LSMA426U	POTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 41 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 41 of 103



DUT: CD835V3 - SN1190

Type: CD835V3 Serial: 1190

Communication System: CW; Frequency: 835 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

835 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x361x1):

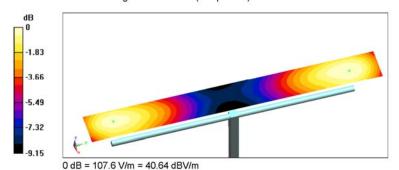
Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 139.3 V/m; Power Drift = -0.10 dB

Applied MIF = 0.00 dB

Average Value of Peak (interpolated) = 106.5 V/m



FCC ID: A3LSMA426U	PCTEST: Froat to be post of @ reserved	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 42 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 42 01 103



DUT: CD1880V3 - SN1176

Type: CD1880V3 Serial: 1176

Communication System: CW; Frequency: 1880 MHz;

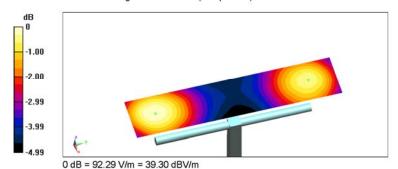
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

1880 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 142.7 V/m; Power Drift = 0.10 dB
Applied MIF = 0.00 dB
Average Value of Peak (interpolated) = 90.2 V/m



FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 43 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 43 01 103



DUT: CD2600V3 - SN1013

Type: CD2600V3 Serial: 1013

Communication System: CW; Frequency: 2600 MHz;

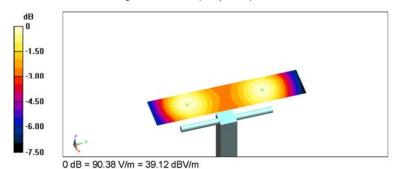
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

2600 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 67.39 V/m; Power Drift = 0.04 dB
Applied MIF = 0.00 dB
Average Value of Peak (interpolated) = 89.6 V/m



FCC ID: A3LSMA426U	PCTEST* Road to be post of \$\infty\$ resources	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 44 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 44 of 103



DUT: CD2600V3 - SN1013

Type: CD2600V3 Serial: 1013

Communication System: CW; Frequency: 2600 MHz;

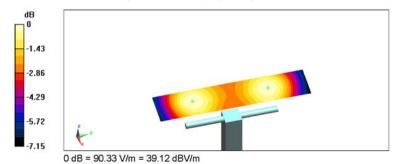
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

2600 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 67.81 V/m; Power Drift = 0.09 dB
Applied MIF = 0.00 dB
Average Value of Peak (interpolated) = 90.2 V/m



FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 45 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		raye 45 01 103



DUT: CD3500V3 - SN1005

Type: CD3500V3 Serial: 1005

Communication System: CW; Frequency: 3500 MHz;

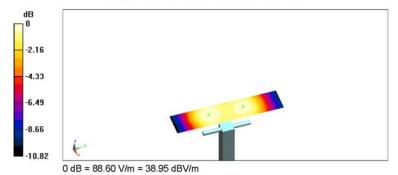
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

3500 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 40.62 V/m; Power Drift = 0.09 dB
Applied MIF = 0.00 dB
Average Value of Peak (interpolated) = 88.2 V/m



FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 46 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 46 of 103



DUT: CD3500V3 - SN1005

Type: CD3500V3 Serial: 1005

Communication System: CW; Frequency: 3900 MHz;

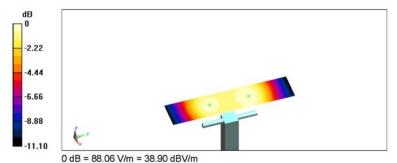
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

3900 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 36.03 V/m; Power Drift = 0.01 dB
Applied MIF = 0.00 dB
Average Value of Peak (interpolated) = 86.4 V/m



FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 47 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 47 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:8

Communication System: CDMA; Frequency: 820.1 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

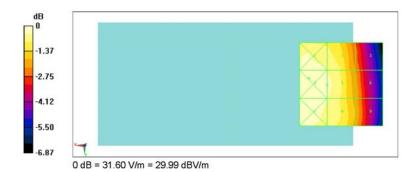
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

Extended Cell. CDMA Mid Channel Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 26.69 V/m; Power Drift = 0.03 dB
Applied MIF = 3.10 dB
RF audio interference level = 29.77 dBV/m
Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
29.84 dBV/m	29.52 dBV/m	27.71 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
29.99 dBV/m	29.77 dBV/m	28.03 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
29.94 dBV/m	29.6 dBV/m	28.16 dBV/m



FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 49 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 48 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:8

Communication System: CDMA; Frequency: 1851.25 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

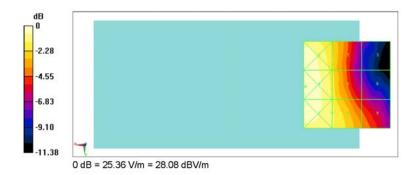
PCS CDMA Low Channel Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 13.28 V/m; Power Drift = 0.15 dB Applied MIF = 3.10 dB RF audio interference level = 26.75 dBV/m

Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
27.95 dBV/m	26 dBV/m	21.11 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
28.08 dBV/m	26.43 dBV/m	22.47 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
28 dBV/m	26.75 dBV/m	24.33 dBV/m



FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 40 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 49 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:8.3

Communication System: GSM; Frequency: 824.2 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

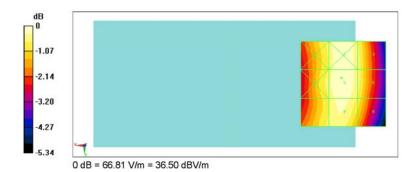
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

GSM850 Low Channel Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 62.57 V/m; Power Drift = -0.03 dB Applied MIF = 3.55 dB RF audio interference level = 36.50 dBV/m Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
35.95 dBV/m	36.48 dBV/m	35.96 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
36.04 dBV/m	36.5 dBV/m	35.97 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
35.88 dBV/m	36.28 dBV/m	35.7 dBV/m



FCC ID: A3LSMA426U	PCTEST: Froad to be port of the second	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 50 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 50 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:8.3

Communication System: GSM; Frequency: 1850.2 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

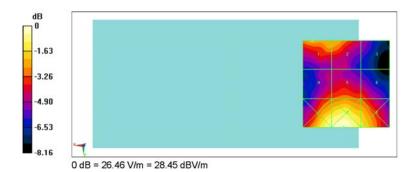
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

GSM1900 Low Channel Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 14.52 V/m; Power Drift = -0.15 dB
Applied MIF = 3.55 dB RF audio interference level = 26.30 dBV/m Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
26.3 dBV/m	26.23 dBV/m	23.85 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
25.2 dBV/m	25.65 dBV/m	25.13 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
28.06 dBV/m	28.45 dBV/m	27.1 dBV/m



FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 51 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 51 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:4.67

Communication System: LTE TDD41; Frequency: 2593 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

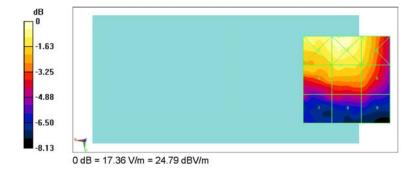
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

TDD LTE Band 41 Power Class 3 Mid Channel, 15MHz, UL-DL 2, 64QAM, 1RB, 36RB Offset Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 15.95 V/m; Power Drift = -0.08 dB Applied MIF = 1.52 dB RF audio interference level = 23.41 dBV/m Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
24.49 dBV/m	24.79 dBV/m	23.72 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
23.18 dBV/m	23.41 dBV/m	23.02 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
		20.68 dBV/m



FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 52 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 52 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:2.42

Communication System: LTE TDD41; Frequency: 2593 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

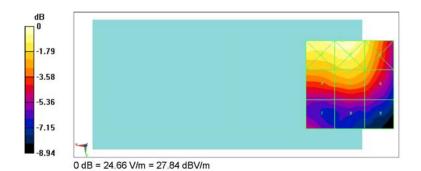
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

TDD LTE Band 41 Power Class 2 Mid Channel, 10MHz, UL-DL 1, 16QAM, 1RB, 0RB Offset Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 29.50 V/m; Power Drift = -0.11 dB
Applied MIF = -1.39 dB
RF audio interference level = 26.07 dBV/m
Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
27.66 dBV/m	27.84 dBV/m	26.69 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
25.75 dBV/m	26.07 dBV/m	25.48 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
Ond / WIT	Ond O mi	Ond o mi-



FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 52 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 53 of 103



Type: Portable Handset Serial: 51730 Backlight off Duty Cycle: 1:4.67

Communication System: LTE Band 48; Frequency: 3555 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

TDD LTE Band 48 Low Channel, 10MHz, UL-DL 2, QPSK, 1RB, 0RB Offset T-Coil Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 34.37 V/m; Power Drift = 0.17 dB Applied MIF = 1.42 dB RF audio interference level = 30.34 dBV/m Emission category: M3

MIF scaled E-field

Grid 1 M4	Grid 2 M3	Grid 3 M3
28.52 dBV/m	30.52 dBV/m	30.51 dBV/m
Grid 4 M4	Grid 5 M3	Grid 6 M3
28.38 dBV/m	30.34 dBV/m	30.34 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
28.42 dBV/m	29.22 dBV/m	29.22 dBV/m



FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags E4 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 54 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:4

Communication System: n41; Frequency: 2640 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

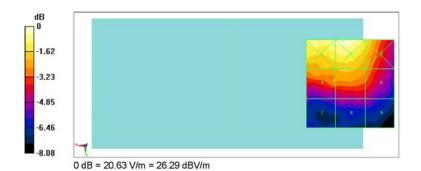
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

NR n41 100MHz High Channel, DFT-s-OFDM, π/2-BPSK, 135RB, 0RB Offset Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 18.04 V/m; Power Drift = -0.03 dB
Applied MIF = 1.39 dB
RF audio interference level = 24.32 dBV/m
Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
26.05 dBV/m	26.29 dBV/m	25.03 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
24.14 dBV/m	24.32 dBV/m	23.76 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4



FCC ID: A3LSMA426U	Proof to be port of the senser	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 55 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 55 of 103



Type: Portable Handset Serial: 13433 Backlight off Duty Cycle: 1:4

Communication System: n77; Frequency: 3750 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

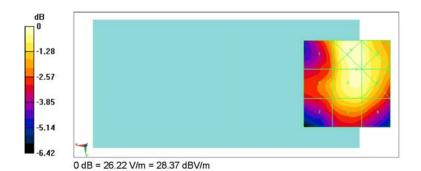
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

NR n77 100MHz mid Channel, DFT-s-OFDM, 64QAM, 1RB, 137RB Offset Acoustic Centered Scan/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 30.36 V/m; Power Drift = 0.09 dB
Applied MIF = 1.45 dB
RF audio interference level = 28.15 dBV/m
Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
26.72 dBV/m	28.37 dBV/m	28.1 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
26.84 dBV/m	28.15 dBV/m	28.04 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
26.34 dBV/m	27.44 dBV/m	27.28 dBV/m



FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg FC of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 56 of 103

CALIBRATION CERTIFICATES 15.

The following pages include the probe calibration used to evaluate HAC for the DUT.

FCC ID: A3LSMA426U	POTEST: Posed to be part of the seasons	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 57 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 57 of 103

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

Cfient P(

Certificate No: EF3-4035 Jan19/2

CALIBRATION CERTIFICATE (Replacement of No: EF3-4035_Jan19)

Object

EF3DV3- SN:4035

Calibration procedure(s)

QA CAL-02.v9, QA CAL-25.v7

Calibration procedure for E-field probes optimized for close near field

evaluations in air

Calibration date:

January 16, 2019

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	04-Apr-18 (No. 217-02672/02673)	Apr-19
Power sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672)	Apr-19
Power sensor NRP-Z91	SN: 103245	04-Apr-18 (No. 217-02673)	Apr-19
Reference 20 dB Attenuator	SN: S5277 (20x)	04-Apr-18 (No. 217-02682)	Apr-19
DAE4	SN: 789	14-Jan-19 (No. DAE4-789_Jan19)	Jan-20
Reference Probe ER3DV6	SN: 2328	09-Oct-18 (No. ER3-2328_Oct18)	Oct-19
Secondary Standards	ID	Check Date (in house)	Scheduled Check
Power meter E4419B	SN: GB41293874	06-Apr-16 (in house check Jun-18)	In house check: Jun-20
Power sensor E4412A	SN: MY41498087	06-Apr-16 (in house check Jun-18)	In house check: Jun-20
Power sensor E4412A	SN: 000110210	06-Apr-16 (in house check Jun-18)	In house check; Jun-20
RF generator HP 8648C	SN: US3642U01700	04-Aug-99 (in house check Jun-18)	In house check: Jun-20
Network Analyzer E8358A	SN: US41080477	31-Mar-14 (in house check Oct-18)	In house check: Oct-19

	Name	Function	Signature	
Calibrated by:	Manu Seltz	Laboratory Technician	AND -	
Approved by:	Katja Pokovic	Technical Manager	Alls	

Issued: February 11, 2019

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: EF3-4035_Jan19/2

Page 1 of 8

FCC ID: A3LSMA426U	PCTEST* Proad to be part of ® summer	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 58 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 56 01 105

Calibration Laboratory of

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étatonnage С Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary:

NORMx,y,z sensitivity in free space DCP diode compression point

CF crest factor (1/duty_cycle) of the RF signal A, B, C, D modulation dependent linearization parameters En incident E-field orientation normal to probe axis incident E-field orientation parallel to probe axis Ep

Polarization φ φ rotation around probe axis

Polarization 9 9 rotation around an axis that is in the plane normal to probe axis (at measurement center),

i.e., 9 = 0 is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system

Calibration is Performed According to the Following Standards:

a) IEEE Std 1309-2005, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", December 2005
b) CTIA Test Plan for Hearing Aid Compatibility, Rev 3.1.1, May 2017

Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization $\vartheta=0$ for XY sensors and $\vartheta=90$ for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- NORM(f)x,y,z = NORMx,y,z * frequency_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

Certificate No: EF3-4035_Jan19/2

Page 2 of 8

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 50 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 59 of 103

DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm $(\mu V/(V/m)^2)$	0.90	0.74	1.20	± 10.1 %
DCP (mV) ^B	96.8	98.5	95.3	

Calibration results for Frequency Response (30 MHz - 6 GHz)

Frequency MHz	Target E-Field V/m	Measured E-field (En) V/m	Deviation E-normal in %	Measured E-field (Ep) V/m	Deviation E-normal in %	Unc (k=2) %
30	77.3	76.8	-0.6%	77.3	0.1%	± 5.1 %
100	77.3	78.2	1.2%	77.8	0.7%	± 5.1 %
450	77.1	78.2	1.5%	77.8	0.9%	± 5.1 %
600	77.1	77.8	0.9%	77.5	0.5%	± 5.1 %
750	77.3	77.7	0.5%	77.2	-0.1%	± 5.1 %
1800	140.3	136.9	-2.4%	137.2	-2.2%	± 5.1 %
2000	133.0	129.4	-2.8%	129.4	-2.7%	± 5.1 %
2200	124.8	121.5	-2.7%	122.7	-1.7%	± 5.1 %
2500	123.7	120.7	-2.4%	121.9	-1.5%	± 5.1 %
3000	78.8	74.8	-5.0%	76.1	-3.5%	± 5.1 %
3500	256.3	248.1	-3.2%	246.0	-4.0%	± 5.1 %
3700	249.7	239.2	-4.2%	239.0	-4.3%	± 5.1 %
5200	50.7	50.7	-0.1%	51.2	0.9%	± 5.1 %
5500	49.6	48.9	-1.5%	48.7	-1.9%	± 5.1 %
5800	48.9	49.1	0.4%	49.3	0.8%	± 5.1 %

Calibration Results for Modulation Response

UID	Communication System Name		A dB	B dB√μV	С	D dB	VR mV	Max dev.	Unc [□] (k=2)
0	CW	Х	0.0	0.0	1.0	0.00	141.5	+ 3.3 %	± 4.7 %
		Υ	0.0	0.0	1.0		125.6		
		Υ	0.0	0.0	1.0		125.1		

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: EF3-4035_Jan19/2

Page 3 of 8

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 60 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 60 01 103

B Numerical linearization parameter: uncertainty not required.
E Uncertainty is determined using the max, deviation from linear response applying rectangular distribution and is expressed for the square of the

EF3DV3 – SN:4035 January 16, 2019

DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

Sensor Frequency Model Parameters

	Sensor X	Sensor Y	Sensor Z
Frequency Corr. (LF)	0.28	0.21	5.68
Frequency Corr. (HF)	2.82	2.82	2.82

Other Probe Parameters

Rectangular
57.9
enabled
disabled
337 mm
12 mm
25 mm
4 mm
1.5 mm
1.5 mm
1.5 mm

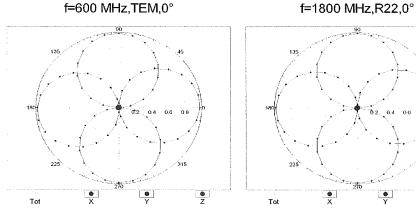
Certificate No: EF3-4035_Jan19/2

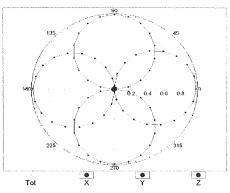
Page 4 of 8

FCC ID: A3LSMA426U	HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 61 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage of or 103

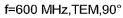
EF3DV3 - SN:4035 January 16, 2019

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$

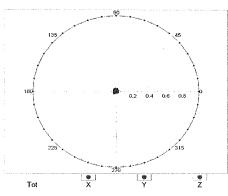


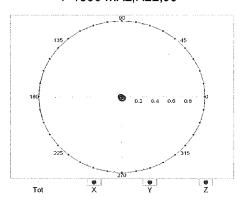


Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$



f=1800 MHz,R22,90°





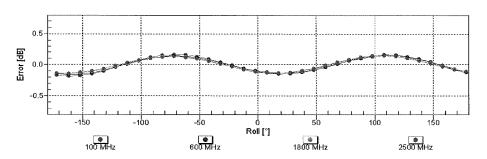
Certificate No: EF3-4035_Jan19/2

Page 5 of 8

FCC ID: A3LSMA426U	PCTEST Proad to be post of the second	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 62 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		raye 02 01 103

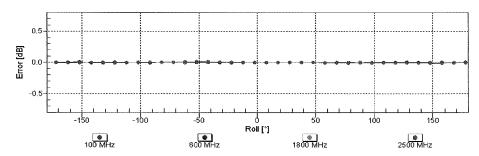
EF3DV3 – SN:4035 January 16, 2019

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$



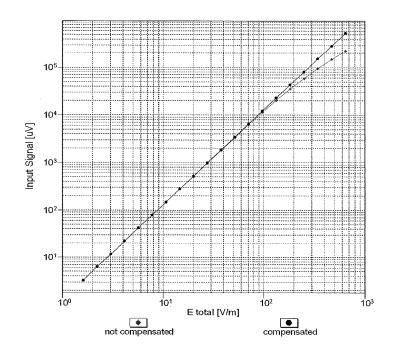
Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

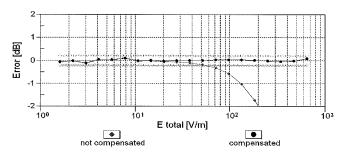
Certificate No: EF3-4035_Jan19/2 Page 6 of 8

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 62 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 63 of 103

EF3DV3 - SN:4035 January 16, 2019

Dynamic Range f(E-field) (TEM cell, f = 900 MHz)





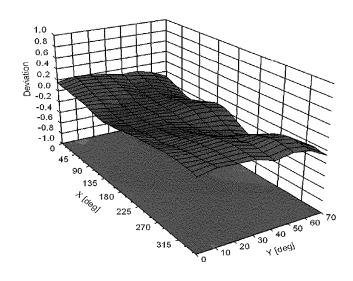
Uncertainty of Linearity Assessment: ± 0.6% (k=2)

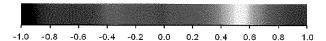
Certificate No: EF3-4035_Jan19/2 Page 7 of 8

FCC ID: A3LSMA426U	PCTEST*	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 64 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 64 of 103

EF3DV3 - SN:4035 January 16, 2019

Deviation from Isotropy in Air Error (ϕ, ϑ) , f = 900 MHz





Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

Certificate No: EF3-4035_Jan19/2

Page 8 of 8

FCC ID: A3LSMA426U	PCTEST: Froat to be post of @ reserved	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 65 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 65 of 103

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schwelzerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 0108

Client

PC Test

Certificate No: EF3_4035_Feb21

CALIBRATION CERTIFICATE Object EF3DV3- SN:4035 Calibration procedure(s) QA CAL-02.v9, QA CAL-25.v7 Calibration procedure for E-field probes optimized for close near field evaluations in air Calibration date: February 15, 2021 This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%. Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	01-Apr-20 (No. 217-03100/03101)	Apr-21
Power sensor NRP-Z91	SN: 103244	01-Apr-20 (No. 217-03100)	Apr-21
Power sensor NRP-Z91	SN: 103245	01-Apr-20 (No. 217-03101)	Apr-21
Reference 20 dB Attenuator	SN: CC2552 (20x)	31-Mar-20 (No. 217-03106)	Apr-21
DAE4	SN: 789	23-Dec-20 (No. DAE4-789_Dec20)	Dec-21
Reference Probe ER3DV6	SN: 2328	05-Oct-20 (No. ER3-2328_Oct20)	Oct-21
Secondary Standards	ID	Check Date (in house)	Scheduled Check
Power meter E4419B	SN: GB41293874	06-Apr-16 (in house check Jun-20)	In house check: Jun-22
Power sensor E4412A	SN: MY41498087	06-Apr-16 (in house check Jun-20)	In house check; Jun-22
Power sensor E4412A	SN: 000110210	06-Apr-16 (in house check Jun-20)	In house check: Jun-22
RF generator HP 8648C	SN: US3642U01700	04-Aug-99 (in house check Jun-20)	In house check: Jun-22
Network Analyzer E8358A	SN: US41080477	31-Mar-14 (in house check Oct-20)	In house check: Oct-21

	Name	Function	Signature
Calibrated by:	Michael Weber	Laboratory Technician	1/1/6/ - 5
	27 22 23 24 24 24 25 25 25 25 25 25 25 25 25 25 25 25 25		MINESCI
Approved by:	Katja Pokovic	Technical Manager	220
			AT UL
	e shall not be reproduced except in ful		Issued: February 16, 2021

Certificate No: EF3_4035_Feb21

Page 1 of 8

FCC ID: A3LSMA426U	Proof to be port of the senser	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 66 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 66 of 103

Calibration Laboratory of

Schmid & Partner **Engineering AG** Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst S Service suisse d'étalonnage C Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

REV 3.5.M

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary:

NORMx,y,z sensitivity in free space DCP diode compression point

CF crest factor (1/duty_cycle) of the RF signal modulation dependent linearization parameters A, B, C, D incident E-field orientation normal to probe axis Ε'n Εp incident E-field orientation parallel to probe axis

Polarization φ ϕ rotation around probe axis

Polarization 9 9 rotation around an axis that is in the plane normal to probe axis (at measurement center),

i.e., $\vartheta = 0$ is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system

Calibration is Performed According to the Following Standards:

a) IEEE Std 1309-2005, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", December 2005

b) CTIA Test Plan for Hearing Aid Compatibility, Rev 3.1.1, May 2017

Methods Applied and Interpretation of Parameters:

NORMx,y,z: Assessed for E-field polarization $\vartheta = 0$ for XY sensors and $\vartheta = 90$ for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).

- $NORM(f)x,y,z = NORMx,y,z * frequency_response$ (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

Certificate No: EF3_4035_Feb21 Page 2 of 8

FCC ID: A3LSMA426U	Portest	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 67 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 67 of 103

EF3DV3 - SN:4035 February 15, 2021

DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm $(\mu V/(V/m)^2)$	0.90	0.73	1.19	± 10.1 %
DCP (mV) ^B	96.3	101.2	98.2	

Frequency	Target E-Field	Measured	Deviation	Measured	Deviation	Unc (k=2)
MHz	V/m	E-field (En)	E-normal	E-field (Ep)	E-normal	% ´
		V/m	in %	V/m	in %	
30	77.1	77.0	-0.2%	77.2	0.1%	± 5.1 %
100	77.2	78.3	1.4%	77.8	0.7%	± 5.1 %
450	77.2	78.4	1.6%	77.9	1.0%	± 5.1 %
600	77.1	77.9	1.1%	77.4	0.5%	± 5.1 %
750	77.1	77.8	0.9%	77.3	0.3%	± 5.1 %
1800	143.1	139.0	-2.8%	139.4	-2.6%	± 5.1 %
2000	135.1	131.3	-2.7%	131.5	-2.6%	± 5.1 %
2200	127.7	123.4	-3.3%	124.5	-2.5%	± 5.1 %
2500	125.5	122.4	-2.5%	123.5	-1.6%	± 5.1 %
3000	79.4	75.6	-4.7%	76.7	-3.3%	± 5.1 %
3500	256.9	246.8	-3.9%	243.9	-4.8%	± 5.1 %
3700	251.2	240.8	-4.2%	237.9	-5.0%	± 5.1 %
5200	50.8	51.4	1.3%	51.7	1.9%	± 5.1 %
5500	47.0	46.8	-0.5%	48.2	2.7%	± 5.1 %
5800	48.8	48.6	-0.6%	47.1	-3.6%	± 5.1 %

Calibration Results for Modulation Response

UID	Communication System Name		A dB	B dB√μV	С	D dB	VR mV	Max dev.	Unc ^E (k=2)
0	CW	X	0.0	0.0	1.0	0.00	141.8	± 3.8 %	± 4.7 %
		Y	0.0	0.0	1.0		172.6		
		Z	0.0	0.0	1.0		171.7		

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: EF3_4035_Feb21

Page 3 of 8

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 60 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 68 of 103

B Numerical linearization parameter: uncertainty not required.
E Uncertainty is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

Sensor Frequency Model Parameters

	Sensor X	Sensor Y	Sensor Z
Frequency Corr. (LF)	0.22	0.19	5.72
Frequency Corr. (HF)	2.82	2.82	2.82

Other Probe Parameters

Sensor Arrangement	Rectangular
Connector Angle (°)	-126.8
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	12 mm
Tip Length	25 mm
Tip Diameter	4 mm
Probe Tip to Sensor X Calibration Point	1.5 mm
Probe Tip to Sensor Y Calibration Point	1.5 mm
Probe Tip to Sensor Z Calibration Point	1.5 mm

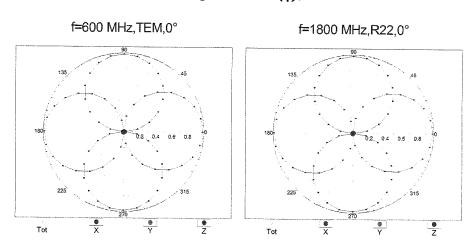
Certificate No: EF3_4035_Feb21

Page 4 of 8

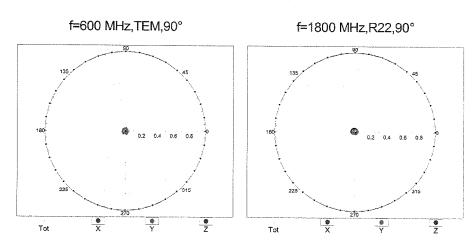
FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RE EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 69 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 09 01 103

EF3DV3 - SN:4035 February 15, 2021

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$



Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$



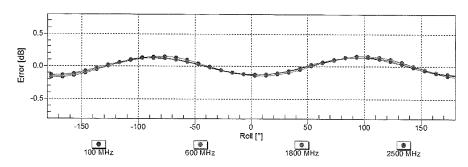
Certificate No: EF3_4035_Feb21 Page 5 of 8

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 70 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 70 01 103

© 2021 PCTEST

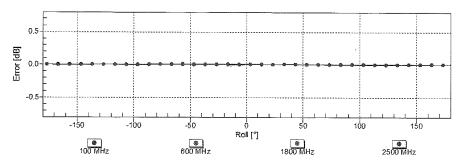
EF3DV3 – SN:4035 February 15, 2021

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

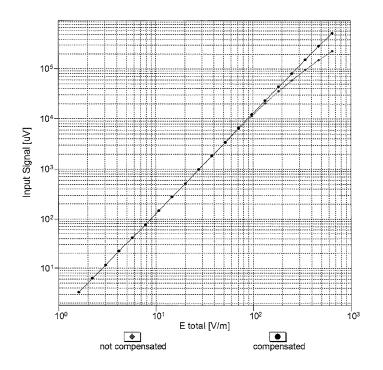
Certificate No: EF3_4035_Feb21

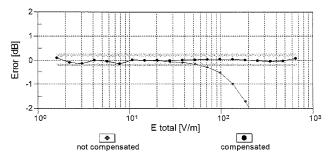
Page 6 of 8

FCC ID: A3LSMA426U	PCTEST*	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 71 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		

EF3DV3 - SN:4035 February 15, 2021

Dynamic Range f(E-field) (TEM cell, f = 900 MHz)





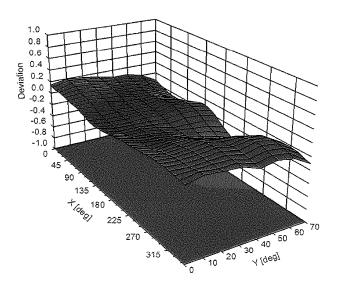
Uncertainty of Linearity Assessment: ± 0.6% (k=2)

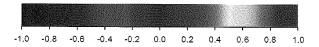
Certificate No: EF3_4035_Feb21 Page 7 of 8

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 70 of 100
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 72 of 103
© 2021 PCTEST				REV 3.5.M

EF3DV3 - SN:4035 February 15, 2021

Deviation from Isotropy in Air Error (ϕ, ϑ) , f = 900 MHz





Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

Certificate No: EF3_4035_Feb21

Page 8 of 8

FCC ID: A3LSMA426U	PCTEST: Froud to be port of the secure	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 72 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 73 of 103

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S

C

S

Schweizerlscher Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client

PC Test

Certificate No: CD835V3-1190_Mar19

Dbject	CD835V3 - SN: 1190					
Calibration procedure(s)	QA CAL-20.v7 Calibration Proce	QA CAL-20.v7 Calibration Procedure for Validation Sources in air				
Calibration date:	March 14, 2019					
The measurements and the unce	ortainties with confidence proceed in the closed laborator	onal standards, which realize the physical unit robability are given on the following pages and ry facility: environment temperature $(22 \pm 3)^{\circ}$ C	i are part of the certificate.			
Calibration Equipment used (M&	1	5 15 1 (S 1) 1 N 1	Scheduled Calibration			
Primary Standards	ID#	Cal Date (Certificate No.)	Apr-19			
Power meter NRP	SN: 104778	04-Apr-18 (No. 217-02672/02673) 04-Apr-18 (No. 217-02672)	Apr-19			
Power sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672)	Apr-19			
Power sensor NRP-Z91	SN: 103245	04-Apr-18 (No. 217-02073)	Apr-19			
Reference 20 dB Attenuator	SN: 5058 (20k)	04-Apr-18 (No. 217-02663)	Apr-19			
Type-N mismatch combination	SN: 5047.2 / 06327	03-Jan-19 (No. EF3-4013_Jan19)	Jan-20			
Probe EF3DV3 DAE4	SN: 4013 SN: 781	09-Jan-19 (No. DAE4-781_Jan19)	Jan-20			
Secondary Standards	ID#	Check Date (in house)	Scheduled Check			
Power meter Agilent 4419B	SN: GB42420191	09-Oct-09 (in house check Oct-17)	In house check: Oct-20			
Power sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Oct-17)	In house check: Oct-20			
Power sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Oct-17)	In house check: Oct-20			
RF generator R&S SMT-06	SN: 832283/011	27-Aug-12 (in house check Oct-17)	In house check: Oct-20			
Network Analyzer HP 8358A	SN: US41080477	31-Mar-14 (in house check Oct-18)	In house check: Oct-19			
•			Gardina 1			
	Name	Function	Signature			
	Claudio Leubler	Laboratory Technician				
Calibrated by:		Technical Manager	alm			
Calibrated by: Approved by:	Katja Pokovic	rechnical wanager	that the			

Certificate No: CD835V3-1190_Mar19

Page 1 of 5

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 74 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 74 01 103

Calibration Laboratory of Schmid & Partner **Engineering AG**

Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

References

ANSI-C63.19-2011 [1] American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the
coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%

Certificate No: CD835V3-1190_Mar19 Page 2 of 5

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 75 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage 75 of 105

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	835 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 835 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	106.8 V/m = 40.57 dBV/m	
Maximum measured above low end	100 mW input power	104.0 V/m = 40.34 dBV/m	
Averaged maximum above arm	100 mW input power	105.4 V/m ± 12.8 % (k=2)	

Appendix (Additional assessments outside the scope of SCS 0108)

Antenna Parameters

Frequency	Return Loss	Impedance	
800 MHz	16.9 dB	39.7 Ω - 7.7 jΩ	
835 MHz	30.7 dB	48.8 Ω + 2.6 jΩ	
880 MHz	18.1 dB	55.0 Ω - 12.2 jΩ	
900 MHz	18.5 dB	47.5 Ω - 11.4 jΩ	
945 MHz	22.9 dB	46.9 Ω + 6.2 jΩ	

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

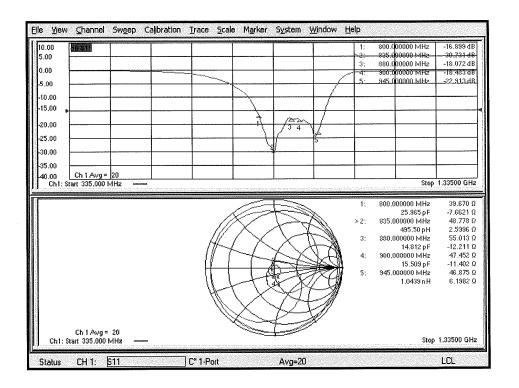
Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

Certificate No: CD835V3-1190_Mar19 Page 3 of 5

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga 76 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 76 of 103

Impedance Measurement Plot



Certificate No: CD835V3-1190_Mar19

Page 4 of 5

FCC ID: A3LSMA426U	PCTEST Road to be post of the resource	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 77 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 77 of 103

DASY5 E-field Result

Date: 14.03.2019

Test Laboratory: SPEAG Lab2

DUT: HAC-Dipole 835 MHz; Type: CD835V3; Serial: CD835V3 - SN: 1190

Communication System: UID 0 - CW; Frequency: 835 MHz Medium parameters used: $\sigma = 0$ S/m, $\epsilon_r = 1$; $\rho = 0$ kg/m³ Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

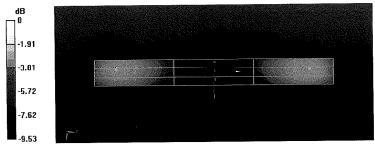
- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 835 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

Dipole E-Field measurement @ 835MHz/E-Scan - 835MHz d=15mm/Hearing Aid Compatibility Test (41x361x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 128.4 V/m; Power Drift = -0.02 dB Applied MIF = 0.00 dBRF audio interference level = 40.57 dBV/m Emission category: M3

MIF scaled E-field

	OLIG E LINE	Grid 3 M3 40.32 dBV/m
Grid 4 M4 35,33 dBV/m	Grid 5 M4 35.75 dBV/m	
Grid 7 M3 40.18 dBV/m	0110 0 1120	Grid 9 M3 40.53 dBV/m



0 dB = 106.8 V/m = 40.57 dBV/m

Certificate No: CD835V3-1190_Mar19

Page 5 of 5

FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:			Page 78 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable	Portable Handset		Page 76 01 103

© 2021 PCTEST

Calibration Laboratory of

Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client

PC Test

Accreditation No.: SCS 0108

Certificate No: CD1880V3-1176_Mar19

CALIBRATION CERTIFICATE CD1880V3 - SN: 1176 Object QA CAL-20.v7 Calibration procedure(s) Calibration Procedure for Validation Sources in air March 14, 2019 Calibration date: This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%. Calibration Equipment used (M&TE critical for calibration) Scheduled Calibration ID# Cal Date (Certificate No.) Primary Standards 04-Apr-18 (No. 217-02672/02673) Apr-19 SN: 104778 Power meter NRP Apr-19 04-Apr-18 (No. 217-02672) SN: 103244 Power sensor NRP-Z91 Apr-19 Power sensor NRP-Z91 SN: 103245 04-Apr-18 (No. 217-02673) SN: 5058 (20k) 04-Apr-18 (No. 217-02682) Apr-19 Reference 20 dB Attenuator 04-Apr-18 (No. 217-02683) Apr-19 SN: 5047.2 / 06327 Type-N mismatch combination 03-Jan-19 (No. EF3-4013_Jan19) Jan-20 Probe EF3DV3 SN: 4013 Jan-20 SN: 781 09-Jan-19 (No. DAE4-781_Jan19) DAE4 Scheduled Check Check Date (in house) ID# Secondary Standards In house check: Oct-20 SN: GB42420191 09-Oct-09 (in house check Oct-17) Power meter Agilent 4419B In house check: Oct-20 SN: US38485102 05-Jan-10 (in house check Oct-17) Power sensor HP E4412A 09-Oct-09 (in house check Oct-17) In house check: Oct-20 SN: US37295597 Power sensor HP 8482A 27-Aug-12 (in house check Oct-17) In house check: Oct-20 RF generator R&S SMT-06 SN: 832283/011 In house check: Oct-19 SN: US41080477 31-Mar-14 (in house check Oct-18) Network Analyzer HP 8358A Function Claudio Leubler Laboratory Technician Calibrated by: Technical Manager Katja Pokovic Approved by: Issued: March 14, 2019 This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: CD1880V3-1176_Mar19

Page 1 of 7

FCC ID: A3LSMA426U	PCTEST HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 70 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 79 of 103

Calibration Laboratory of

Schmid & Partner **Engineering AG** Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst S Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

References

ANSI-C63.19-2011 [1]

Certificate No: CD1880V3-1176_Mar19

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positionina: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.	
	-

Page 2 of 7

FCC ID: A3LSMA426U	PCTEST HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 80 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage ou or 103

© 2021 PCTEST

Measurement Conditions

DASY system configuration, as far as not given on page 1

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	1730 MHz ± 1 MHz 1880 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 1730 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	94.9 V/m = 39.55 dBV/m
Maximum measured above low end	100 mW input power	94.7 V/m = 39.53 dBV/m
Averaged maximum above arm	100 mW input power	94.8 V/m ± 12.8 % (k=2)

Maximum Field values at 1880 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	88.8 V/m = 38.97 dBV/m
Maximum measured above low end	100 mW input power	87.1 V/m = 38.80 dBV/m
Averaged maximum above arm	100 mW input power	88.0 V/m ± 12.8 % (k=2)

Certificate No: CD1880V3-1176_Mar19 Page 3 of 7

FCC ID: A3LSMA426U	PCTEST HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 01 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 81 of 103

REV 3.5.M

Appendix (Additional assessments outside the scope of SCS 0108)

Antenna Parameters

Nominal Frequencies

Frequency	Return Loss	Impedance
1730 MHz	28.1 dB	52.9 Ω + 2.8 jΩ
1880 MHz	20.2 dB	53.1 Ω + 9.6 jΩ
1900 MHz	21.5 dB	54.9 Ω + 7.4 jΩ
1950 MHz	30.2 dB	52.7 Ω + 1.7 jΩ
2000 MHz	19.4 dB	46.3 Ω + 9.7 jΩ

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

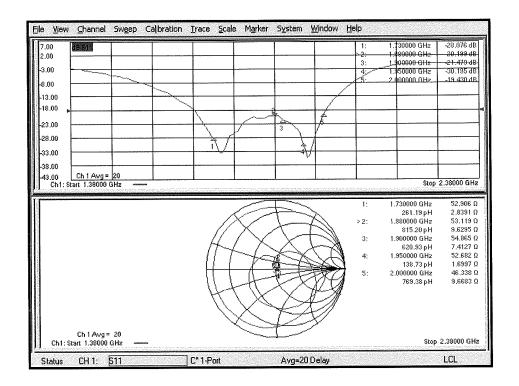
Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

Certificate No: CD1880V3-1176_Mar19 Page 4 of 7

FCC ID: A3LSMA426U	PCTEST HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 92 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 82 of 103

Impedance Measurement Plot



Certificate No: CD1880V3-1176_Mar19

Page 5 of 7

FCC ID: A3LSMA426U	PCTEST* Frond to lie got! of the resources	HAC (RE EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogg 92 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 83 of 103

© 2021 PCTEST

DASY5 E-field Result

Date: 14.03.2019

Test Laboratory: SPEAG Lab2

DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: CD1880V3 - SN: 1176

Communication System: UID 0 - CW; Frequency: 1880 MHz, Frequency: 1730 MHz

Medium parameters used: $\sigma = 0$ S/m, $\varepsilon_r = 1$; $\rho = 0$ kg/m³

Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 1880 MHz, ConvF(1, 1, 1) @ 1730 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

Dipole E-Field measurement @ 1880MHz/E-Scan - 1880MHz d=15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 151.4 V/m; Power Drift = 0.01 dB Applied MIF = 0.00 dBRF audio interference level = 38.97 dBV/m

Emission category: M2

MIF scaled E-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
38.49 dBV/m	38.97 dBV/m	38.94 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
35.8 dBV/m	36.03 dBV/m	36.02 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
38.42 dBV/m	38.8 dBV/m	38.76 dBV/m

Certificate No: CD1880V3-1176_Mar19

Page 6 of 7

FCC ID: A3LSMA426U	PCTEST HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 94 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 84 of 103

Dipole E-Field measurement @ 1880MHz/E-Scan - 1730MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated

grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm

Reference Value = 162.0 V/m; Power Drift = 0.03 dB

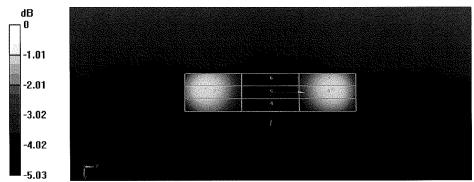
Applied MIF = 0.00 dB

RF audio interference level = 39.55 dBV/m

Emission category: M2

MIF scaled E-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
39.06 dBV/m	39.55 dBV/m	39.52 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
36.69 dBV/m	37.01 dBV/m	36.99 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
39.13 dBV/m	39.53 dBV/m	39.49 dBV/m



0 dB = 88.85 V/m = 38.97 dBV/m

Certificate No: CD1880V3-1176_Mar19 Page 7 of 7

FCC ID: A3LSMA426U	Proof to be port of the seasoners	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 05 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 85 of 103

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S

C

Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 0108

Client

PC Test

Certificate No: CD2600V3-1013_Mar19

CALIBRATION CERTIFICATE CD2600V3 - SN: 1013 Object QA CAL-20.v7 Calibration procedure(s) Calibration Procedure for Validation Sources in air March 14, 2019 Calibration date: This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%. Calibration Equipment used (M&TE critical for calibration) Scheduled Calibration Cal Date (Certificate No.) ID# Primary Standards 04-Apr-18 (No. 217-02672/02673) Power meter NRP SN: 104778 Apr-19 SN: 103244 04-Apr-18 (No. 217-02672) Apr-19 Power sensor NRP-Z91 Apr-19 SN: 103245 04-Apr-18 (No. 217-02673) Power sensor NRP-Z91 Apr-19 Reference 20 dB Attenuator SN: 5058 (20k) 04-Apr-18 (No. 217-02682) Apr-19 Type-N mismatch combination SN: 5047.2 / 06327 04-Apr-18 (No. 217-02683) Probe EF3DV3 SN: 4013 03-Jan-19 (No. EF3-4013_Jan19) Jan-20 09-Jan-19 (No. DAE4-781_Jan19) Jan-20 DAF4 SN: 781 Check Date (in house) Scheduled Check ID# Secondary Standards In house check: Oct-20 SN: GB42420191 09-Oct-09 (in house check Oct-17) Power meter Agilent 4419B In house check: Oct-20 Power sensor HP E4412A SN: US38485102 05-Jan-10 (in house check Oct-17) Power sensor HP 8482A SN: US37295597 09-Oct-09 (in house check Oct-17) In house check: Oct-20 In house check: Oct-20 RF generator R&S SMT-06 SN: 832283/011 27-Aug-12 (in house check Oct-17) 31-Mar-14 (in house check Oct-18) In house check: Oct-19 SN: US41080477 Network Analyzer HP 8358A Name Function Signature Calibrated by: Claudio Leubler Laboratory Technician Approved by: Katja Pokovic Technical Manager Issued: March 14, 2019 This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: CD2600V3-1013_Mar19

Page 1 of 5

FCC ID: A3LSMA426U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 96 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 86 of 103

Calibration Laboratory of Schmid & Partner **Engineering AG**

Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

References

[1] ANSI-C63.19-2011

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncer	rtainty of measurement multiplied by the
coverage factor k=2, which for a normal distribution corresponds to a coverage	verage probability of approximately 95%.

Certificate No: CD2600V3-1013 Mar19 Page 2 of 5

Approved by: PCTEST FCC ID: A3LSMA426U HAC (RF EMISSIONS) TEST REPORT SAMSUNG Quality Manager Filename: Test Dates: DUT Type:

Page 87 of 103 1M2101040001-18-R1.A3L 1/18/2021 - 2/23/2021 Portable Handset © 2021 PCTEST

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	2600 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 2600 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	86.2 V/m = 38.71 dBV/m
Maximum measured above low end	100 mW input power	84.6 V/m = 38.55 dBV/m
Averaged maximum above arm	100 mW input power	85.4 V/m ± 12.8 % (k=2)

Appendix (Additional assessments outside the scope of SCS 0108)

Antenna Parameters

Frequency	Return Loss	Impedance
2450 MHz	23.0 dB	44.5 Ω - 3.8 jΩ
2550 MHz	35.4 dB	50.9 Ω + 1.4 jΩ
2600 MHz	30.1 dB	53.1 Ω - 0.9 jΩ
2650 MHz	28.1 dB	51.7 Ω - 3.6 jΩ
2750 MHz	20.0 dB	45.7 Ω - 8.6 jΩ

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

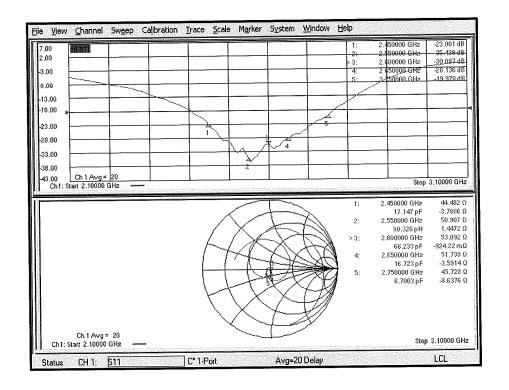
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

Certificate No: CD2600V3-1013_Mar19

Page 3 of 5

FCC ID: A3LSMA426U	Proof to be port of the seasoners	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 90 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 88 of 103

Impedance Measurement Plot



Certificate No: CD2600V3-1013_Mar19

Page 4 of 5

FCC ID: A3LSMA426U	PCTEST Proceed to the post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 89 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		rage og or 103

DASY5 E-field Result

Date: 14.03.2019

Test Laboratory: SPEAG Lab2

DUT: HAC Dipole 2600 MHz; Type: CD2600V3; Serial: CD2600V3 - SN: 1013

Communication System: UID 0 - CW; Frequency: 2600 MHz Medium parameters used: $\sigma = 0$ S/m, $\varepsilon_r = 1$; $\rho = 0$ kg/m³

Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 2600 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

Dipole E-Field measurement @ 2600MHz/E-Scan - 2600MHz d=15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 64.23 V/m; Power Drift = 0.01 dB

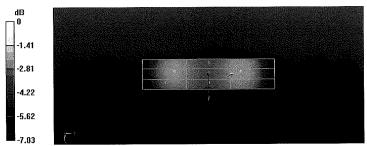
Applied MIF = 0.00 dB

RF audio interference level = 38.71 dBV/m

Emission category: M2

MIF scaled E-field

38.36 dBV/m	38.71 dBV/m	38.67 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
37.8 dBV/m	38.1 dBV/m	38.08 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
38.16 dBV/m	38.55 dBV/m	38.52 dBV/m
Grid 1 M2	Grid 2 M2	Grid 3 M2



0 dB = 86.15 V/m = 38.71 dBV/m

Certificate No: CD2600V3-1013_Mar19

Page 5 of 5

FCC	ID: A3LSMA426U	PCTEST	HAG	C (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filen	ame:	Test Dates:		DUT Type:		Page 90 of 103
1M21	01040001-18-R1.A3L	1/18/2021 - 2/23/2021		Portable Handset		rage 90 01 103

© 2021 PCTEST

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage

S Servizio svizzero di taratura Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 0108

Client

PC Test

Certificate No: CD3500V3-1005_Oct20

Object	CD3500V3 - SN:	1005	
Calibration procedure(s)	QA CAL-20.v7 Calibration Proce	dure for Validation Sources in air	г
Calibration date:	October 20, 2020		
The measurements and the uncert	tainties with confidence particles with confidence particles.	onal standards, which realize the physical uni robability are given on the following pages an γ facility: environment temperature (22 \pm 3)°C	d are part of the certificate.
Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	01-Apr-20 (No. 217-03100/03101)	Apr-21
			- qui ta i
Power sensor NRP-Z91	SN: 103244	01-Apr-20 (No. 217-03100)	Apr-21
Power sensor NRP-Z91 Power sensor NRP-Z91	SN: 103244 SN: 103245	01-Apr-20 (No. 217-03100) 01-Apr-20 (No. 217-03101)	Apr-21
		01-Apr-20 (No. 217-03101)	Apr-21
Power sensor NRP-Z91	SN: 103245	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106)	Apr-21 Apr-21
Power sensor NRP-Z91 Reference 20 dB Attenuator	SN: 103245 SN: BH9394 (20k)	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104)	Apr-21 Apr-21 Apr-21
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106)	Apr-21 Apr-21
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4 Secondary Standards	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013 SN: 781	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19) Check Date (in house)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013 SN: 781	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19) Check Date (in house) 09-Oct-09 (in house check Oct-20)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20 Scheduled Check In house check: Oct-23
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4 Secondary Standards Power meter Agilent 4419B	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013 SN: 781	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19) Check Date (in house) 09-Oct-09 (in house check Oct-20) 05-Jan-10 (in house check Oct-20)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20 Scheduled Check In house check: Oct-23 In house check: Oct-23
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013 SN: 781 ID # SN: GB42420191 SN: US38485102	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19) Check Date (in house) 09-Oct-09 (in house check Oct-20)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20 Scheduled Check In house check: Oct-23
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013 SN: 781 ID # SN: GB42420191 SN: US38485102 SN: US37295597	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19) Check Date (in house) 09-Oct-09 (in house check Oct-20) 05-Jan-10 (in house check Oct-20)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20 Scheduled Check In house check: Oct-23 In house check: Oct-23 In house check: Oct-23
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP B482A RF generator R&S SMT-06 Network Analyzer Agilent E8358A	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013 SN: 781 ID # SN: GB42420191 SN: US38485102 SN: US37295597 SN: 837633/005 SN: US41080477 Name	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19) Check Date (in house) 09-Oct-09 (in house check Oct-20) 05-Jan-10 (in house check Oct-20) 10-Jan-19 (in house check Oct-20) 31-Mar-14 (in house check Oct-20)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20 Scheduled Check In house check: Oct-23
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A RF generator R&S SMT-06	SN: 103245 SN: BH9394 (20k) SN: 310982 / 06327 SN: 4013 SN: 781 ID # SN: GB42420191 SN: US38485102 SN: US37295597 SN: 837633/005 SN: US41080477	01-Apr-20 (No. 217-03101) 31-Mar-20 (No. 217-03106) 31-Mar-20 (No. 217-03104) 31-Dec-19 (No. EF3-4013_Dec19) 27-Dec-19 (No. DAE4-781_Dec19) Check Date (in house) 09-Oct-09 (in house check Oct-20) 05-Jan-10 (in house check Oct-20) 10-Jan-19 (in house check Oct-20) 31-Mar-14 (in house check Oct-20)	Apr-21 Apr-21 Apr-21 Dec-20 Dec-20 Scheduled Check In house check: Oct-23 In house check: Oct-21

Certificate No: CD3500V3-1005_Oct20

Page 1 of 7

FCC ID: A3LSMA426U	PCTEST Phod to be port of the summer	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 01 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 91 of 103

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

References

[1] ANSI-C63.19-2011
American National Standard, Methods of Measurement of Compatibility between Wireless Communications
Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
 (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
 In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a
 distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
 figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
 is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
 directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a Vector Network Analyzer.
 The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic E-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the
coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%

Certificate No: CD3500V3-1005_Oct20	Page 2 of 7

FCC ID: A3LSMA426U	PCTEST HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 92 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 92 01 103

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.4
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	3500 MHz ± 1 MHz 3900 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 3500 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	85.3 V/m = 38.61 dBV/m	
Maximum measured above low end	100 mW input power	83.6 V/m = 38.44 dBV/m	
Averaged maximum above arm	100 mW input power	84.4 V/m ± 12.8 % (k=2)	

Maximum Field values at 3900 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	82.0 V/m = 38.28 dBV/m	
Maximum measured above low end	100 mW input power	79.9 V/m = 38.05 dBV/m	
Averaged maximum above arm	100 mW input power	81.0 V/m ± 12.8 % (k=2)	

Certificate No: CD3500V3-1005_Oct20

Page 3 of 7

FCC ID: A3LSMA426U	PCTEST: HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 93 of 103
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Fage 93 01 103

Appendix (Additional assessments outside the scope of SCS 0108)

Antenna Parameters

Nominal Frequencies

Frequency	Return Loss	Impedance	
3300 MHz	22.3 dB	58.2 Ω + 0.9 jΩ	
3400 MHz	31.4 dB	52.7 Ω - 0.2 jΩ	
3500 MHz	25.0 dB	55.4 Ω - 2.4 jΩ	
3600 MHz	21.1 dB	49.4 Ω - 8.8 jΩ	
3700 MHz	19.6 dB	41.0 Ω - 3.2 jΩ	

Additional Frequencies

Frequency	Return Loss	Impedance
3900 MHz	17.0 dB	47.7 Ω + 13.8 jΩ

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

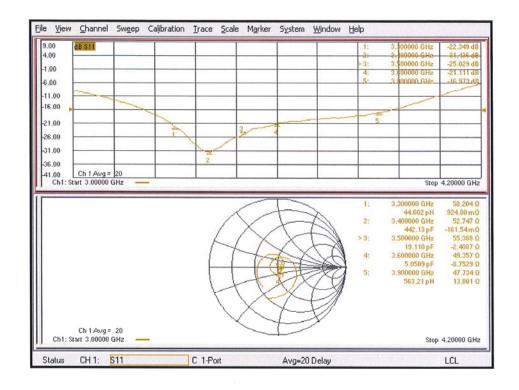
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

Certificate No: CD3500V3-1005_Oct20

Page 4 of 7

FCC ID: A3LSMA426U	PCTEST* Proud to its port of the exercise	HAC (RE EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 94 of 103
1M2101040001-18-R1.A	3L 1/18/2021 - 2/23/2021	Portable Handset		Fage 94 01 103

Impedance Measurement Plot



Certificate No: CD3500V3-1005_Oct20

Page 5 of 7

FCC ID: A3LSMA426U	PCTEST: HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 05 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 95 of 103

DASY5 E-field Result

Date: 20.10.2020

Test Laboratory: SPEAG Lab2

DUT: HAC Dipole 3500 MHz; Type: CD3500V3; Serial: CD3500V3 - SN: 1005

Communication System: UID 0 - CW; Frequency: 3500 MHz, Frequency: 3900 MHz

Medium parameters used: $\sigma = 0$ S/m, $\epsilon_r = 1$; $\rho = 0$ kg/m³

Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 3500 MHz, ConvF(1, 1, 1) @ 3900 MHz; Calibrated: 31.12.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 27.12.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.4(1527); SEMCAD X 14.6.14(7483)

Dipole E-Field measurement @ 3500MHz/E-Scan - 3500MHz d=15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 34.56 V/m; Power Drift = 0.03 dB

Applied MIF = 0.00 dB

RF audio interference level = 38.61 dBV/m

Emission category: M2

MIF scaled E-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
38.24 dBV/m	38.44 dBV/m	38.36 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
38.41 dBV/m	38.61 dBV/m	38.5 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
38.41 dBV/m	38.6 dBV/m	38.49 dBV/m

Certificate No: CD3500V3-1005_Oct20

Page 6 of 7

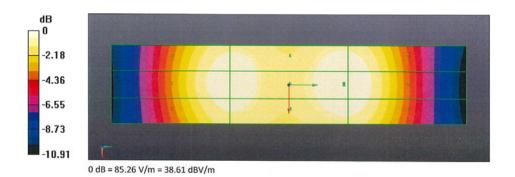
FCC ID: A3LSMA426U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 06 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 96 of 103

Dipole E-Field measurement @ 3500MHz/E-Scan - 3900MHz d=15mm/Hearing Aid Compatibility Test (41x181x1);

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 31.52 V/m; Power Drift = -0.01 dB Applied MIF = 0.00 dB RF audio interference level = 38.28 dBV/m Emission category: M2

MIF scaled E-field

	Grid 2 M2 38.05 dBV/m	the state of the s
	Grid 5 M2 38.28 dBV/m	
Grid 7 M2	Grid 8 M2	Grid 9 M2
38.09 dBV/m	38.25 dBV/m	38.13 dBV/m



Certificate No: CD3500V3-1005_Oct20

Page 7 of 7

FCC ID: A3LSMA426U	PCTEST Phod to be port of a secure	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 07 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 97 of 103

16. CONCLUSION

The measurements taken in accordance with the procedures provided in the CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017, indicate that the wireless communications device complies with the HAC limits specified in the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

FCC ID: A3LSMA426U	PCTEST: Front to be port of a removed	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 00 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 98 of 103

17. REFERENCES

- ANSI C63.19-2011, American National Standard for Methods of Measurement of Compatibility between Wireless communication devices and Hearing Aids.", New York, NY, IEEE, May 2011
- 2. CTIA Certification Program, "Test Plan for Hearing Aid Compatibility Rev 3.1.1", Washington, DC, CTIA, May 2017
- 3. FCC Office of Engineering and Technology KDB, "285076 D01 HAC Guidance v05," September 13, 2017
- FCC Office of Engineering and Technology KDB, "285076 D02 T-Coil Testing for CMRS IP v03," September 13, 2017
- FCC Public Notice DA 06-1215, Wireless Telecommunications Bureau and Office of Engineering and Technology Clarify
 Use of Revised Wireless Phone Hearing Aid Compatibility Standard, June 6, 2006
- 6. FCC 3G Review Guidance, Laboratory Division OET FCC, May/June 2006
- Berger, H. S., "Compatibility Between Hearing Aids and Wireless Devices," Electronic Industries Forum, Boston, MA, May, 1997
- 8. Berger, H. S., "Hearing Aid and Cellular Phone Compatibility: Working Toward Solutions," Wireless Telephones and Hearing Aids: New Challenges for Audiology, Gallaudet University, Washington, D.C., May, 1997 (To be reprinted in the American Journal of Audiology).
- 9. Berger, H. S., "Hearing Aid Compatibility with Wireless Communications Devices, "IEEE International Symposium on Electromagnetic Compatibility, Austin, TX, August, 1997.
- Bronaugh, E. L., "Simplifying EMI Immunity (Susceptibility) Tests in TEM Cells," in the 1990 IEEE International Symposium on Electromagnetic Compatibility Symposium Record, Washington, D.C., August 1990, pp. 488-491
- 11. Byme, D. and Dillon, H., The National Acoustics Laboratory (NAL) New Procedure for Selecting the Gain and Frequency Response of a Hearing Aid, Ear and Hearing 7:257-265, 1986.
- Crawford, M. L., "Measurement of Electromagnetic Radiation from Electronic Equipment using TEM Transmission Cells," U.S. Department of Commerce, National Bureau of Standards, NBSIR 73-306, Feb. 1973.
- 13. Crawford, M. L., and Workman, J. L., "Using a TEM Cell for EMC Measurements of Electronic Equipment," U.S. Department of Commerce, National Bureau of Standards. Technical Note 1013, July 1981.
- EHIMA GSM Project, Development phase, Project Report (1st part) Revision A. Technical-Audiological Laboratory and Telecom Denmark, October 1993.
- 15. EHIMA GSM Project, Development phase, Part II Project Report. Technical-Audiological Laboratory and Telecom Denmark, June 1994.
- EHIMA GSM Project Final Report, Hearing Aids and GSM Mobile Telephones: Interference Problems, Methods of Measurement and Levels of Immunity. Technical-Audiological Laboratory and Telecom Denmark, 1995.
- 17. HAMPIS Report, Comparison of Mobile phone electromagnetic near field with an upscaled electromagnetic far field, using hearing aid as reference, 21 October 1999.
- 18. Hearing Aids/GSM, Report from OTWIDAM, Technical-Audiological Laboratory and Telecom Denmark, April 1993.
- 19. IEEE 100, The Authoritative Dictionary of IEEE Standards Terms, Seventh Edition.
- 20. Joyner, K. H, et. al., Interference to Hearing Aids by the New Digital Mobile Telephone System, Global System for Mobile (GSM) Communication Standard, National Acoustic Laboratory, Australian Hearing Series, Sydney 1993.
- 21. Joyner, K. H., et. al., Interference to Hearing Aids by the Digital Mobile Telephone System, Global System for Mobile Communications (GSM), NAL Report #131, National Acoustic Laboratory, Australian Hearing Series, Sydney, 1995.
- 22. Kecker, W. T., Crawford, M. L., and Wilson, W. A., "Contruction of a Transverse Electromagnetic Cell", U.S. Department of Commerce, National Bureau of Standards, Technical Note 1011, Nov. 1978.

FCC ID: A3LSMA426U	PCTEST Proact to be post of the resource	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 00 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 99 of 103

- 23. Konigstein, D., and Hansen, D., "A New Family of TEM Cells with enlarged bandwidth and Optimized working Volume," in the Proceedings of the 7th International Symposium on EMC, Zurich, Switzerland, March 1987; 50:9, pp. 127-132.
- 24. Kuk, F., and Hjorstgaard, N. K., "Factors affecting interference from digital cellular telephones," Hearing Journal, 1997; 50:9, pp 32-34.
- 25. Ma, M. A., and Kanda, M., "Electromagnetic Compatibility and Interference Metrology," U.S. Department of Commerce, National Bureau of Standards, Technical Note 1099, July 1986, pp. 17-43.
- 26. Ma, M. A., Sreenivashiah, I., and Chang, D. C., "A Method of Determining the Emission and Susceptibility Levels of Electrically Small Objects Using a TEM Cell," U.S. Department of Commerce, National Bureau of Standards, Technial Note 1040, July 1981.
- 27. McCandless, G. A., and Lyregaard, P. E., Prescription of Gain/Output (POGO) for Hearing Aids, Hearing Instruments 1:16-21, 1983
- 28. Skopec, M., "Hearing Aid Electromagnetic Interference from Digital Wireless Telephones, "IEEE Transactions on Rehabilitation Engineering, vol. 6, no. 2, pp. 235-239, June 1998.
- Technical Report, GSM 05.90, GSM EMC Considerations, European Telecommunications Standards Institute, January 1993.
- 30. Victorian, T. A., "Digital Cellular Telephone Interference and Hearing Aid Compatibility—an Update," Hearing Journal 1998; 51:10, pp. 53-60
- 31. Wong, G. S. K., and Embleton, T. F. W., eds., AIP Handbook of Condenser Microphones: Theory, Calibration and Measurements, AIP Press.

FCC ID: A3LSMA426U	PCTEST: Front to be post of @ reserved	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 100 of 102
1M2101040001-18-R1.A3L	1/18/2021 - 2/23/2021	Portable Handset		Page 100 of 103